

# MICROSCOPIC INVESTIGATION OF MATERIALS LIMITATIONS OF SUPERCONDUCTING RF CAVITIES



Bakhrom Oripov  
Steven M. Anlage



This work is funded by US Department of Energy  
grant # DESC0017931 and CNAM

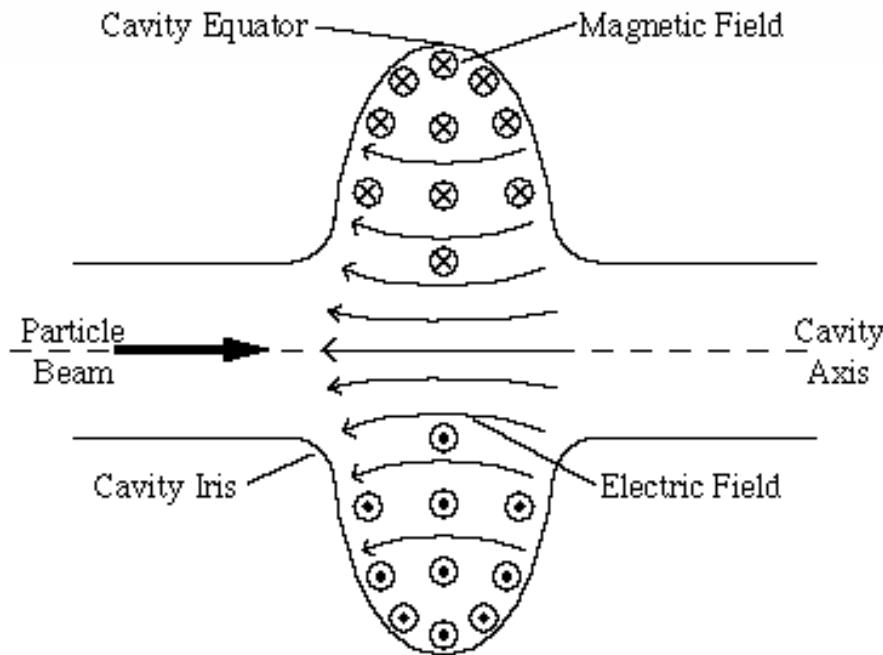
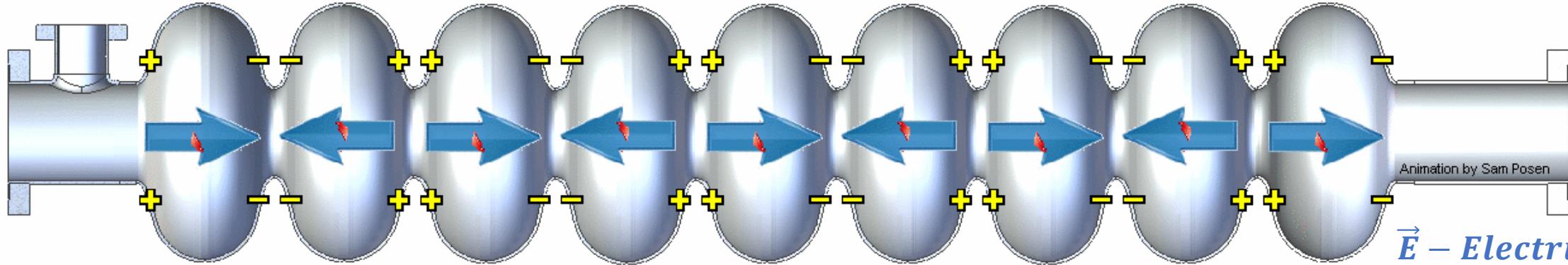


# Outline:

1. **What** is the issue?
2. **Why** is SRF material science needed?
3. **How** Magnetic Microwave Microscopy works?
4. **What** did we measure?
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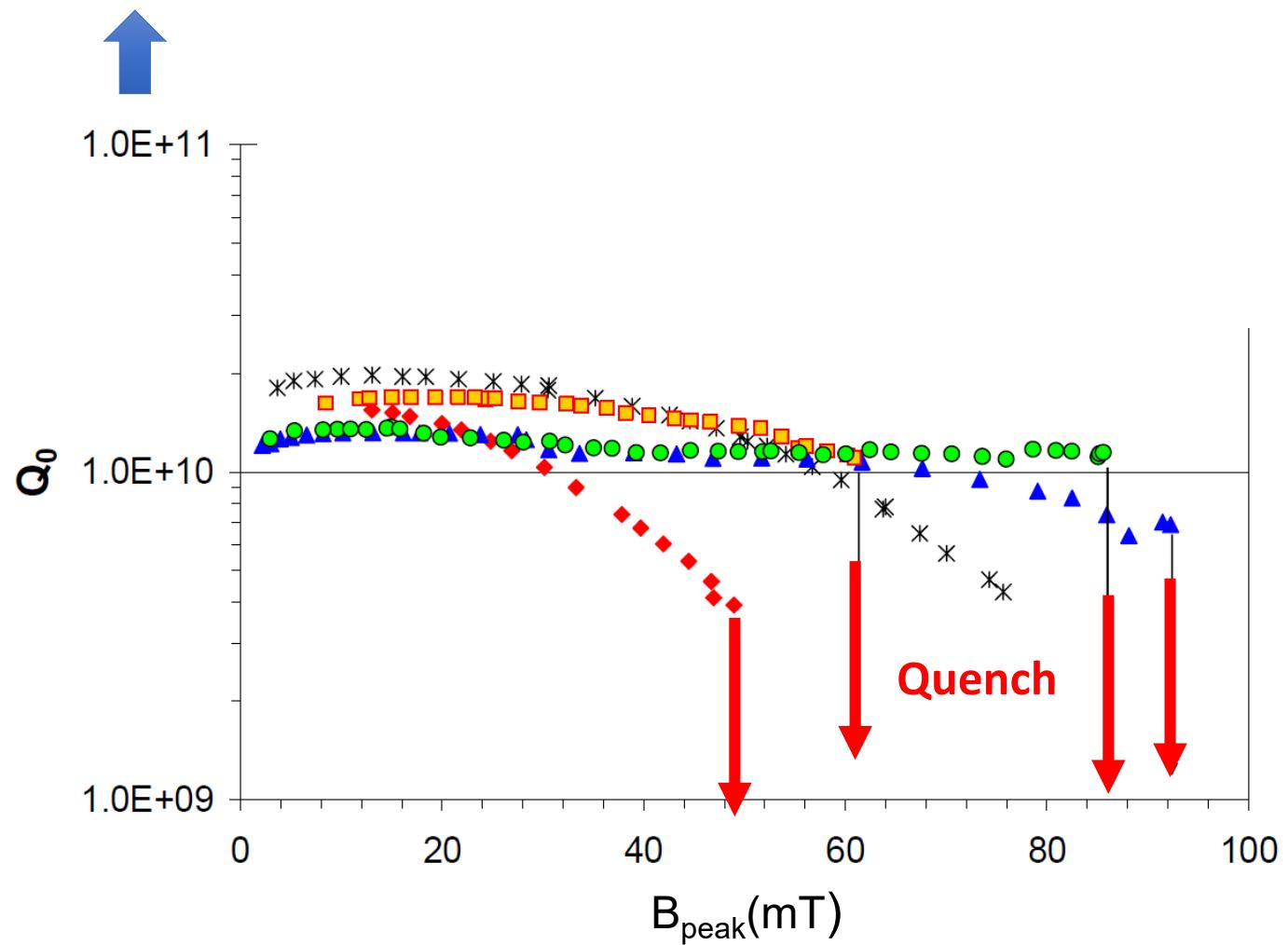
# Superconducting Radio Frequency (SRF) Cavity



$\vec{E}$  – Electric Field  
 $\vec{B}$  – Magnetic Field  
Charges  
Beam Bunch

Increase Q => decrease  
required power

# Quality factor vs Peak Field



RF test results at 2.0 K for the 1.497 GHz, 5-cell HC cavity after different surface preparation processes.

Increase max  $E_{\text{acc}}$  =>  
decrease accelerator  
length

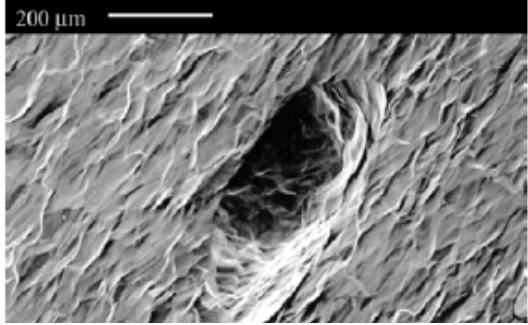
Gianluigi Ciovati, Peter Kneisel, and Ganapati R. Myneni "America's Overview of Superconducting Science and Technology of Ingot Niobium" AIP Conference Proceedings 1352, 25 (2011); doi: 10.1063/1.3579221

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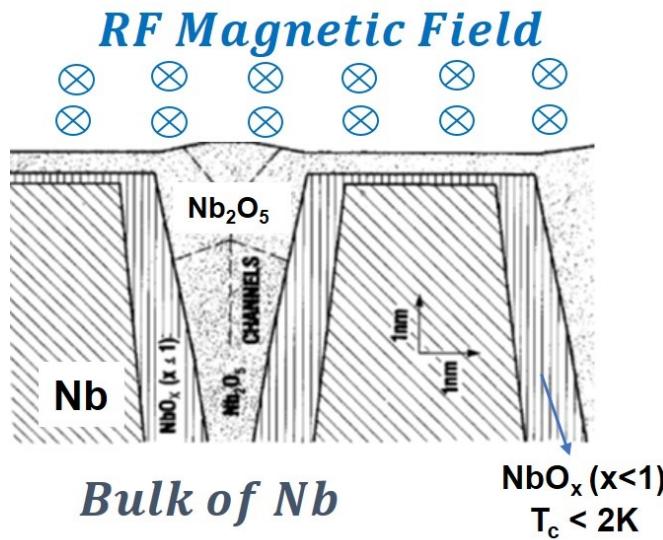


# Defects/Processes limiting SRF Performance



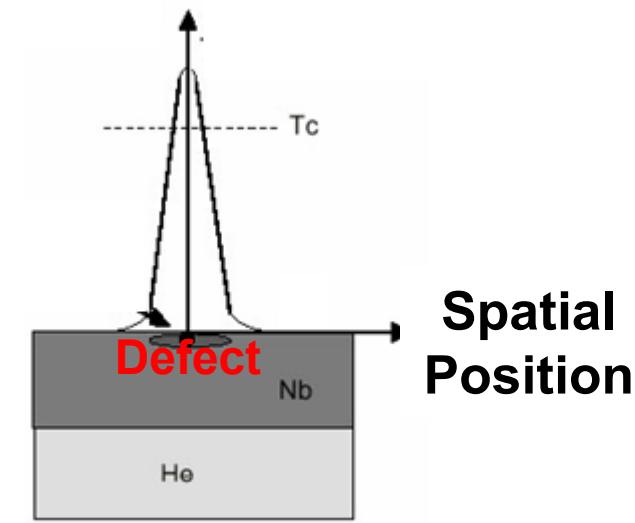
500 x 200  $\mu\text{m}$  pit

1. Surface Roughness
2. Pits
3. Welds
4. Grain Boundaries
5. Nb Oxides
6. Hydrogen Poisoning
7. Magnetic Impurities
8. Trapped Flux

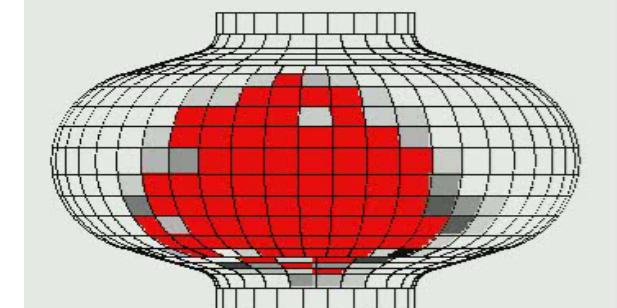


Bulk of Nb

NbO<sub>x</sub> ( $x < 1$ )  
 $T_c < 2\text{K}$



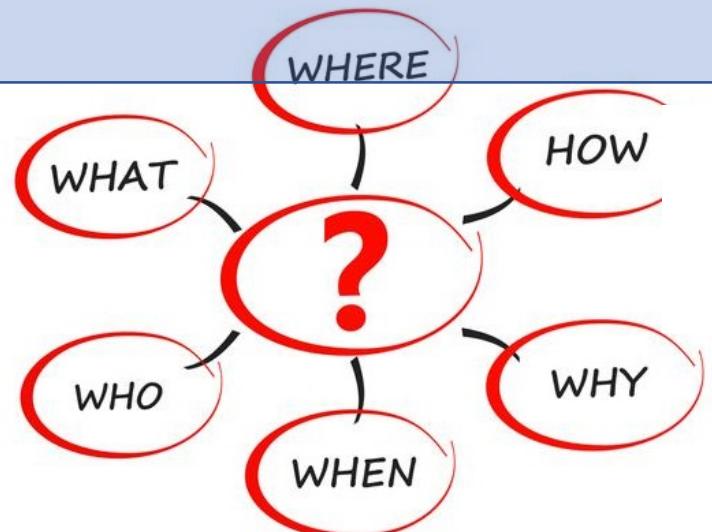
Cavity Temperature Map



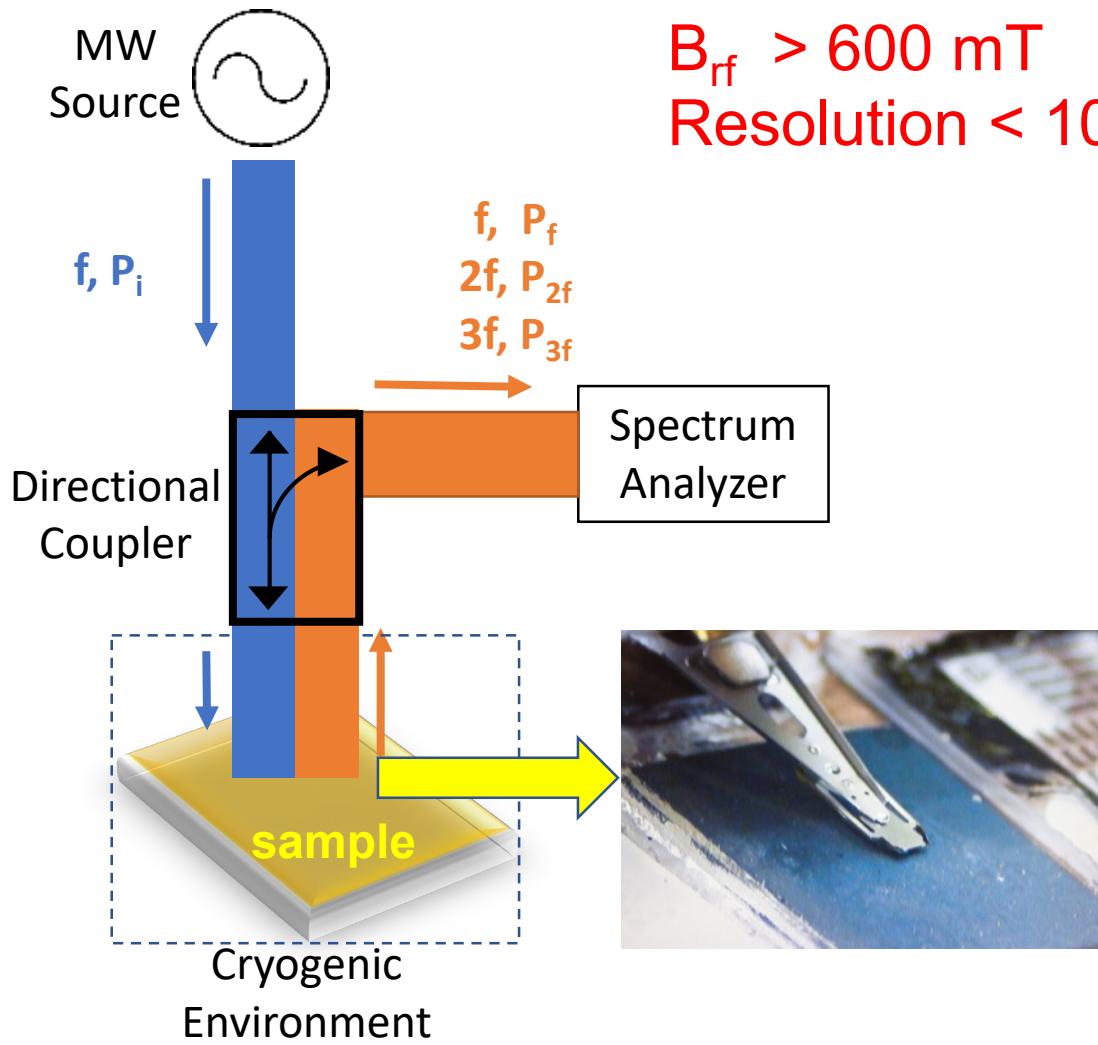
A. Gössel D. Reschke  
(DESY, 2008)

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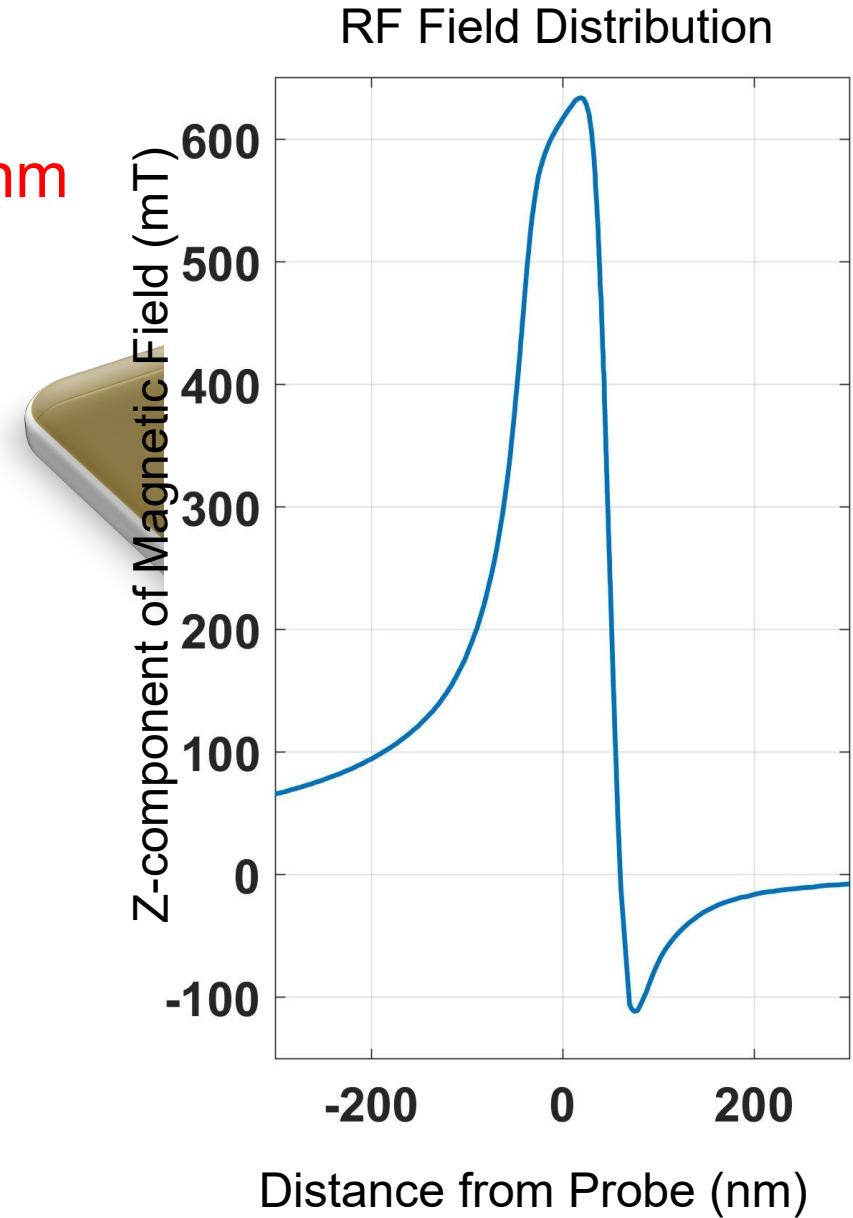
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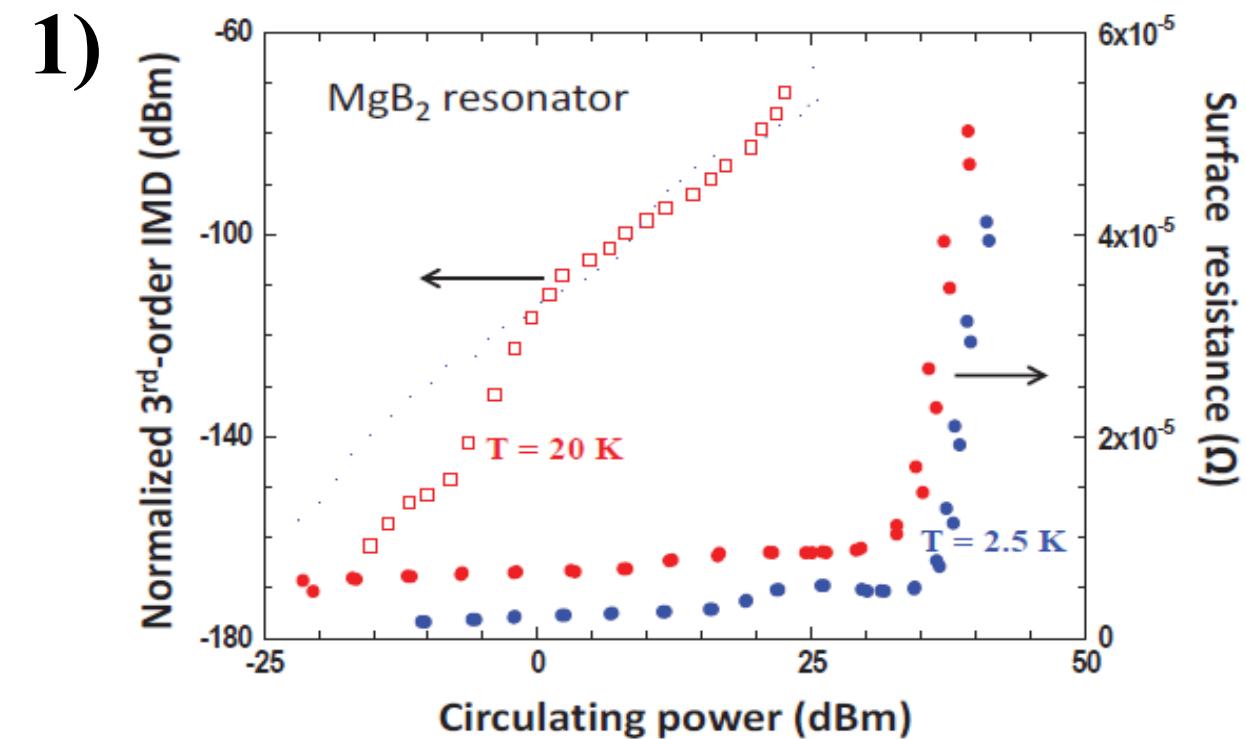
# Near-Field $B_{rf}$ Microscope



$B_{rf} > 600 \text{ mT}$   
Resolution < 100 nm



# Why Harmonics?



D. E. Oates, Y. D. Agassi, B. H. Moeckly,  
IEEE TRANSACTIONS ON APPLIED SUPERCONDUCTIVITY, VOL. 17, NO. 2, JUNE 2007

2) **Superconductor is the main source of Nonlinearity**

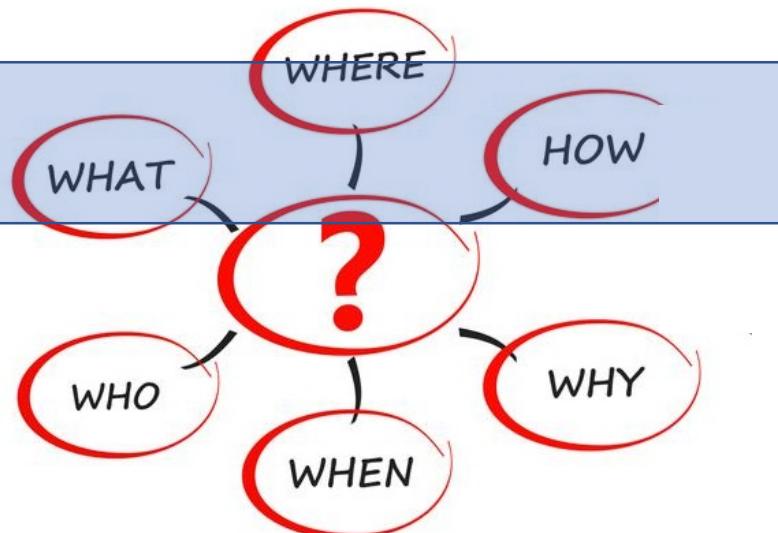
## Advantages of this method

	SRF	Magnetic Probe Microscopy
Temperature	2 K	$3.6\text{ K} - T_c$
RF Magnetic Field	$\approx 200\text{ mT}$	$\approx 200\text{ mT}$
Frequency	1.3 GHz	1.0 – 6.0 GHz

- RF Characterization
  - Localized / No Edge Effect
- Can Measure Flat Samples of any shape

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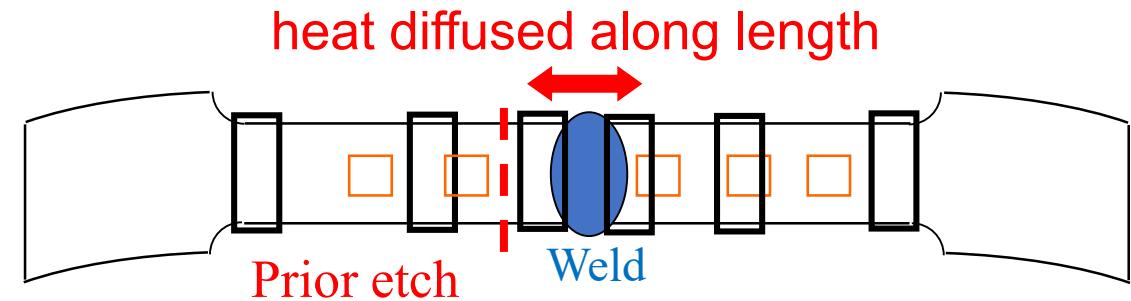


# Bulk Nb Sample

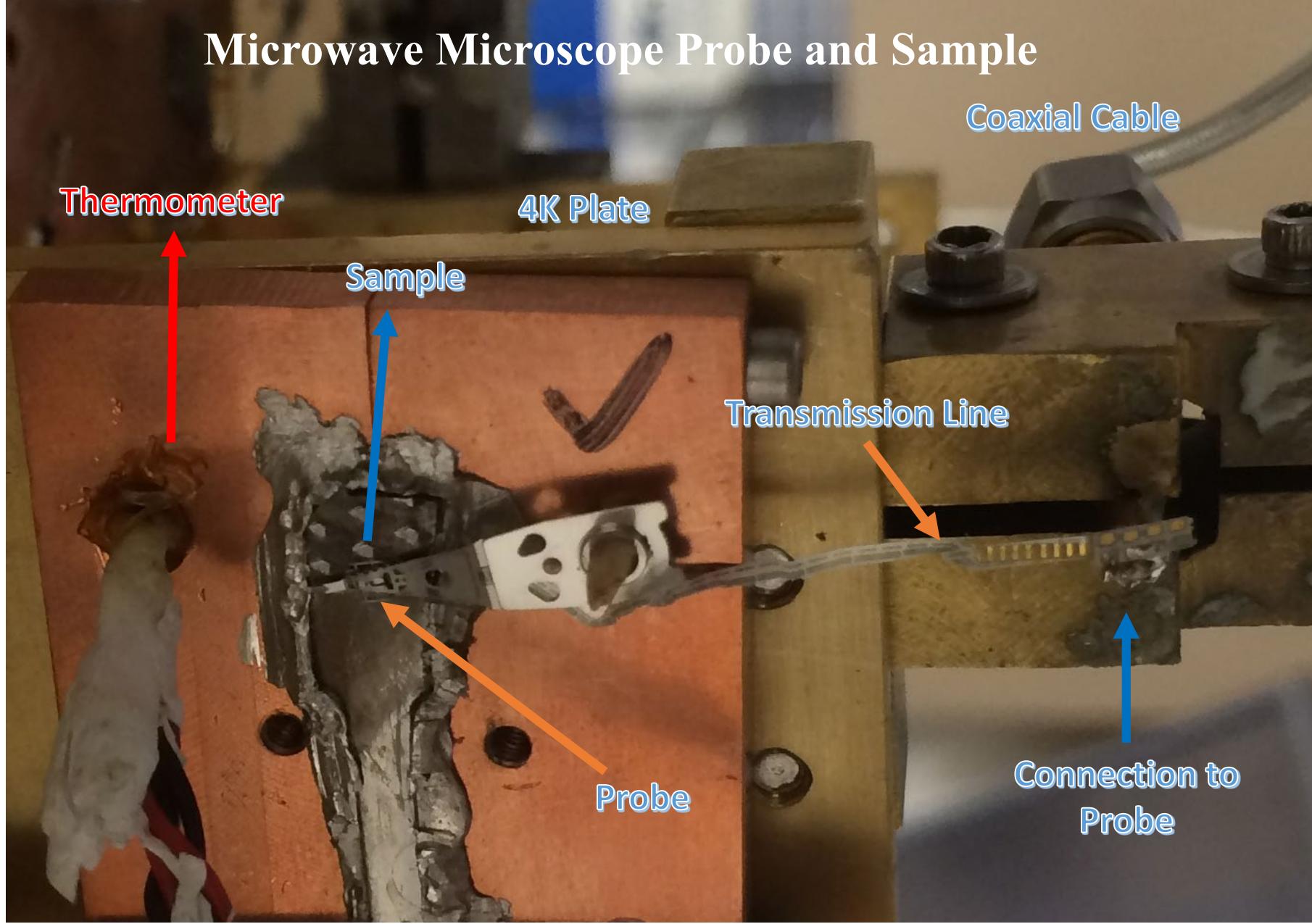
Deformed ( $\epsilon \sim 0.4$ ) single crystals  
pulled apart,  
Etched for 10 min  
then welded back together

Sample prepared by Tom Bieler,  
Michigan State University

MICHIGAN STATE  
UNIVERSITY

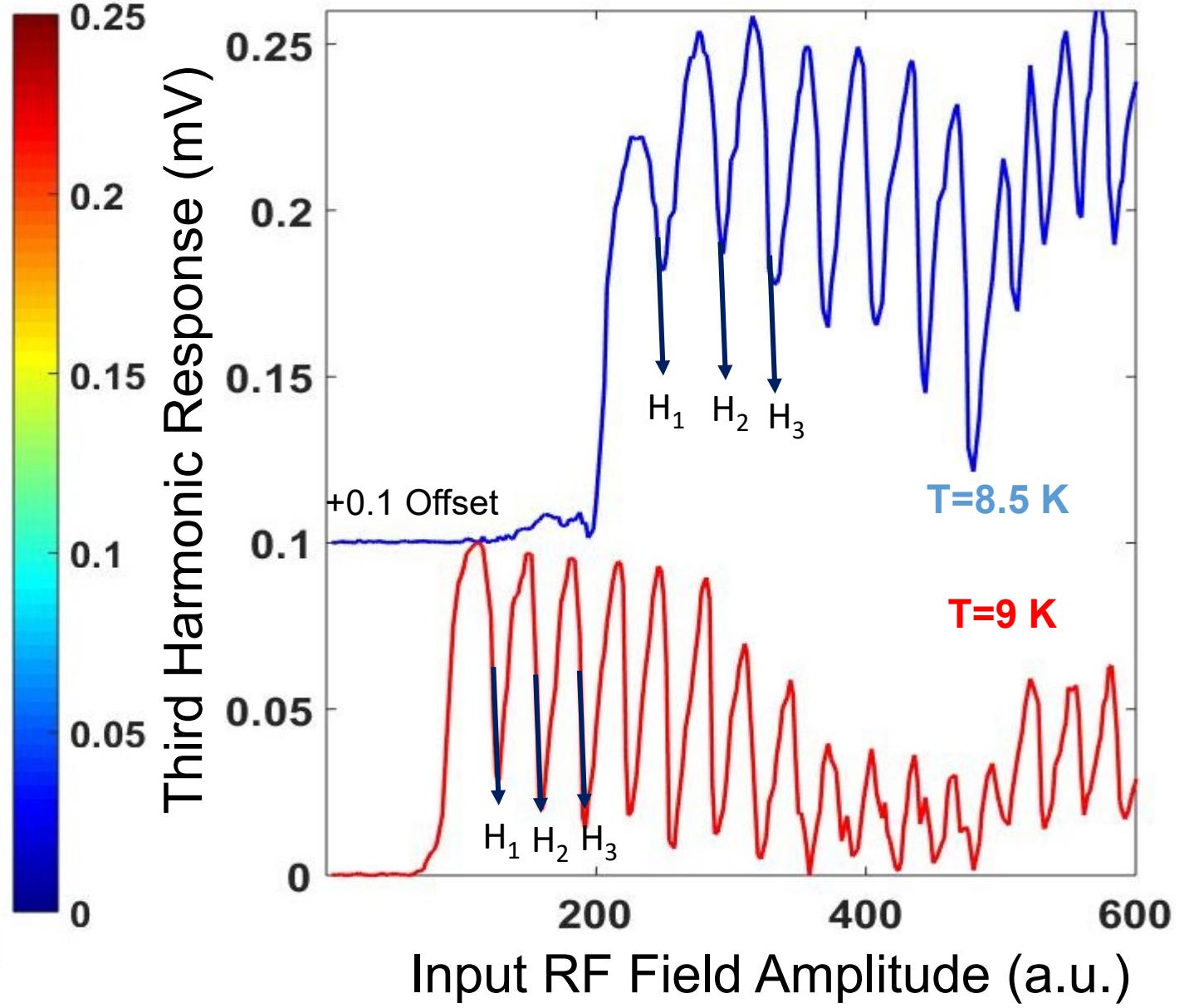
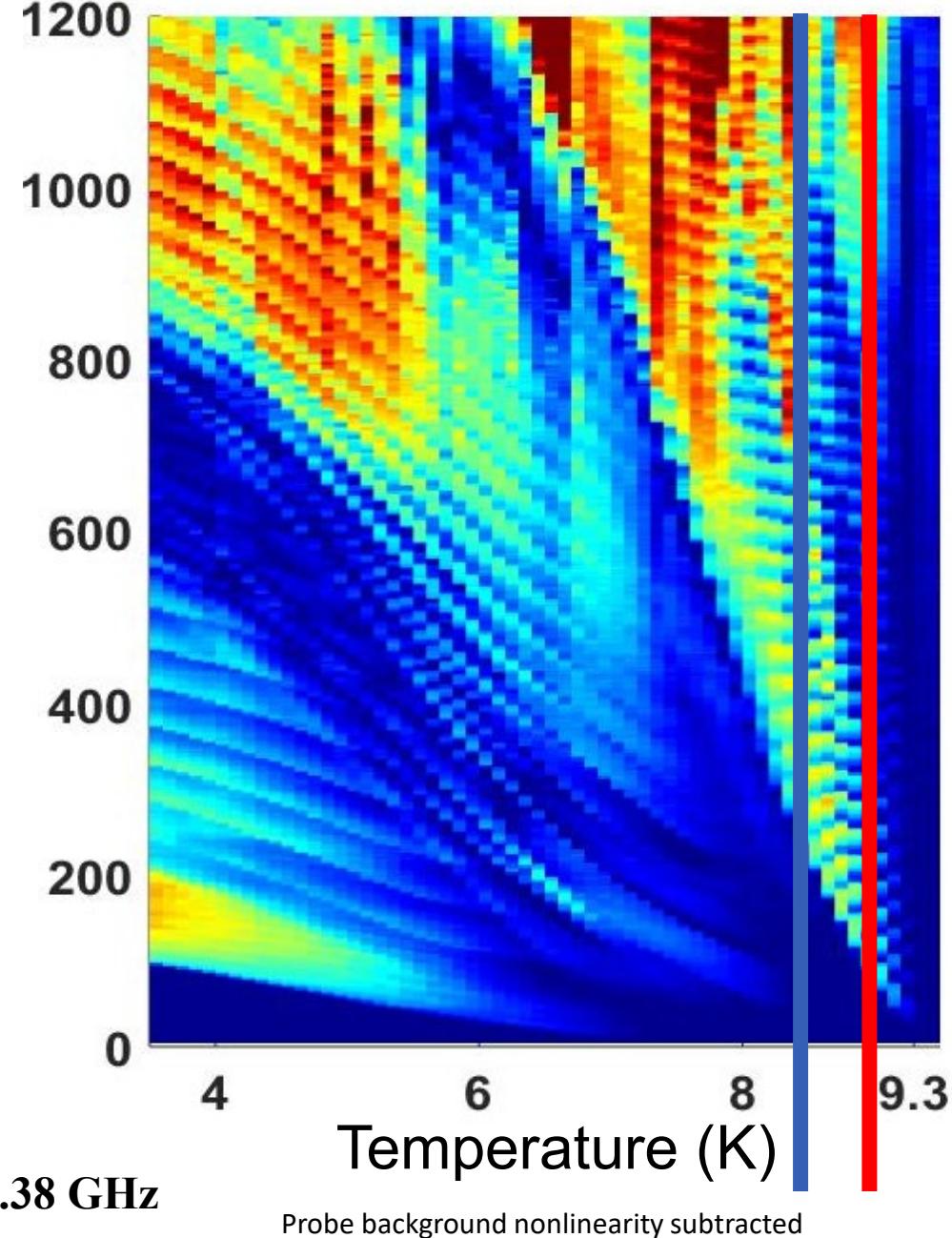


# Microwave Microscope Probe and Sample

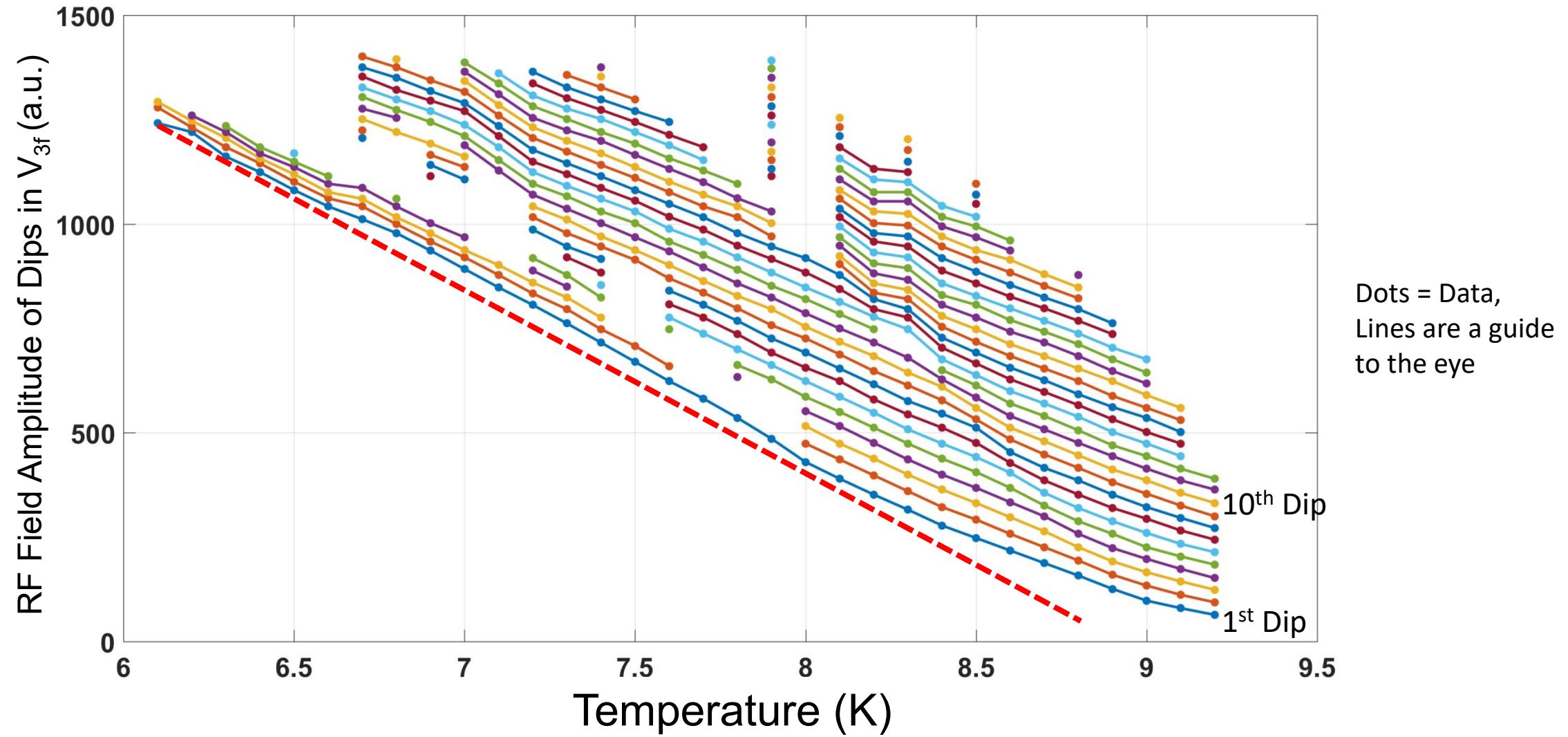


# Bulk Nb Data: Periodicity in Harmonic Response

Input RF Field Amplitude (a.u.)

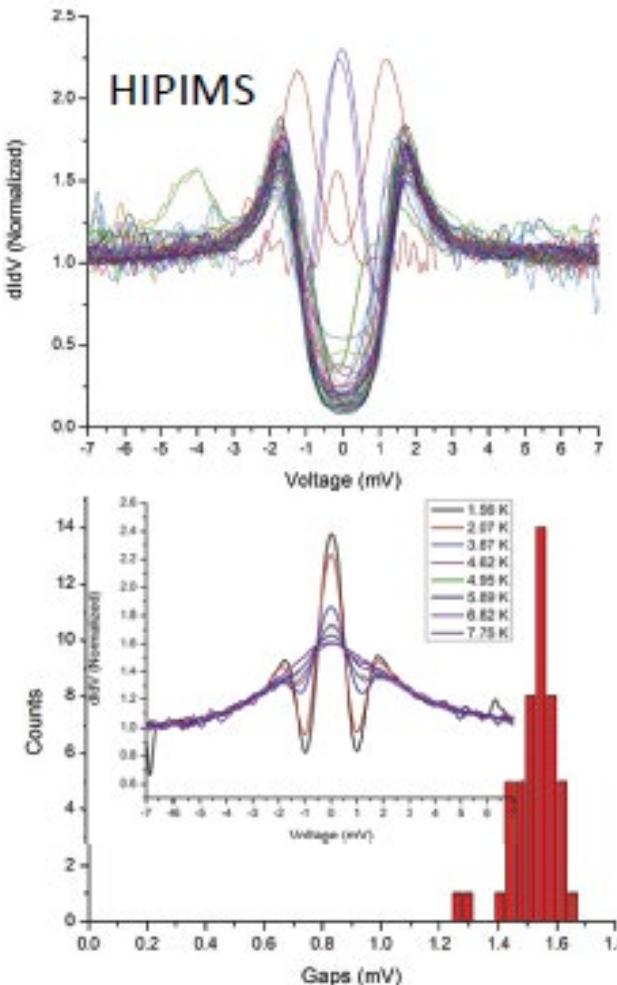


# Bulk Nb Data: Closer look at Dips



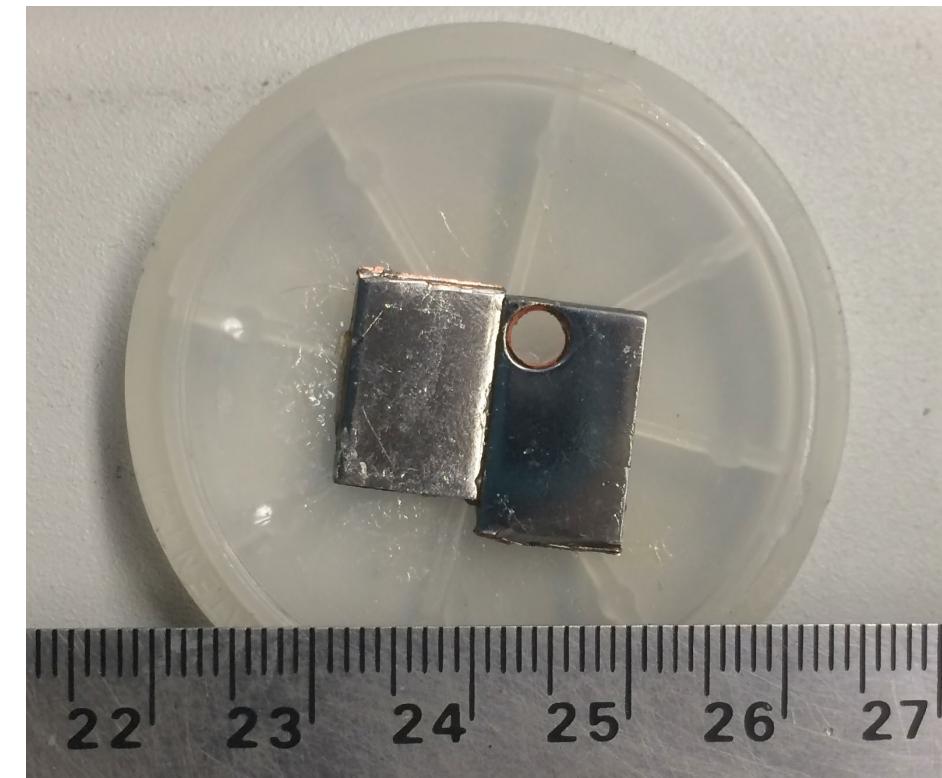
# Nb Film on Copper samples from CERN

- Deposited by high-power impulse magnetron sputtering (HIPIMS)
- Highly Granular (grain size around 10 nm)
- 1  $\mu\text{m}$  Nb / Cu

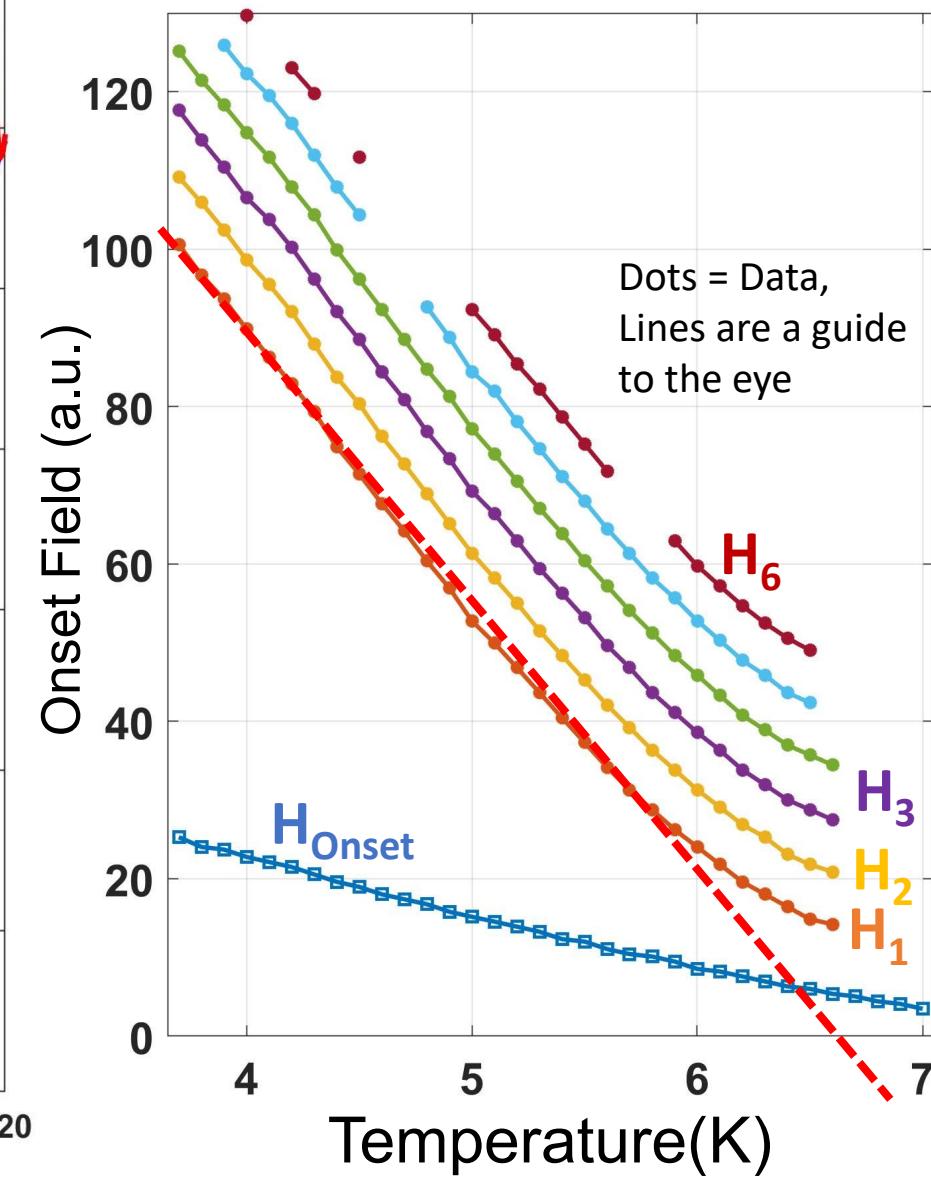
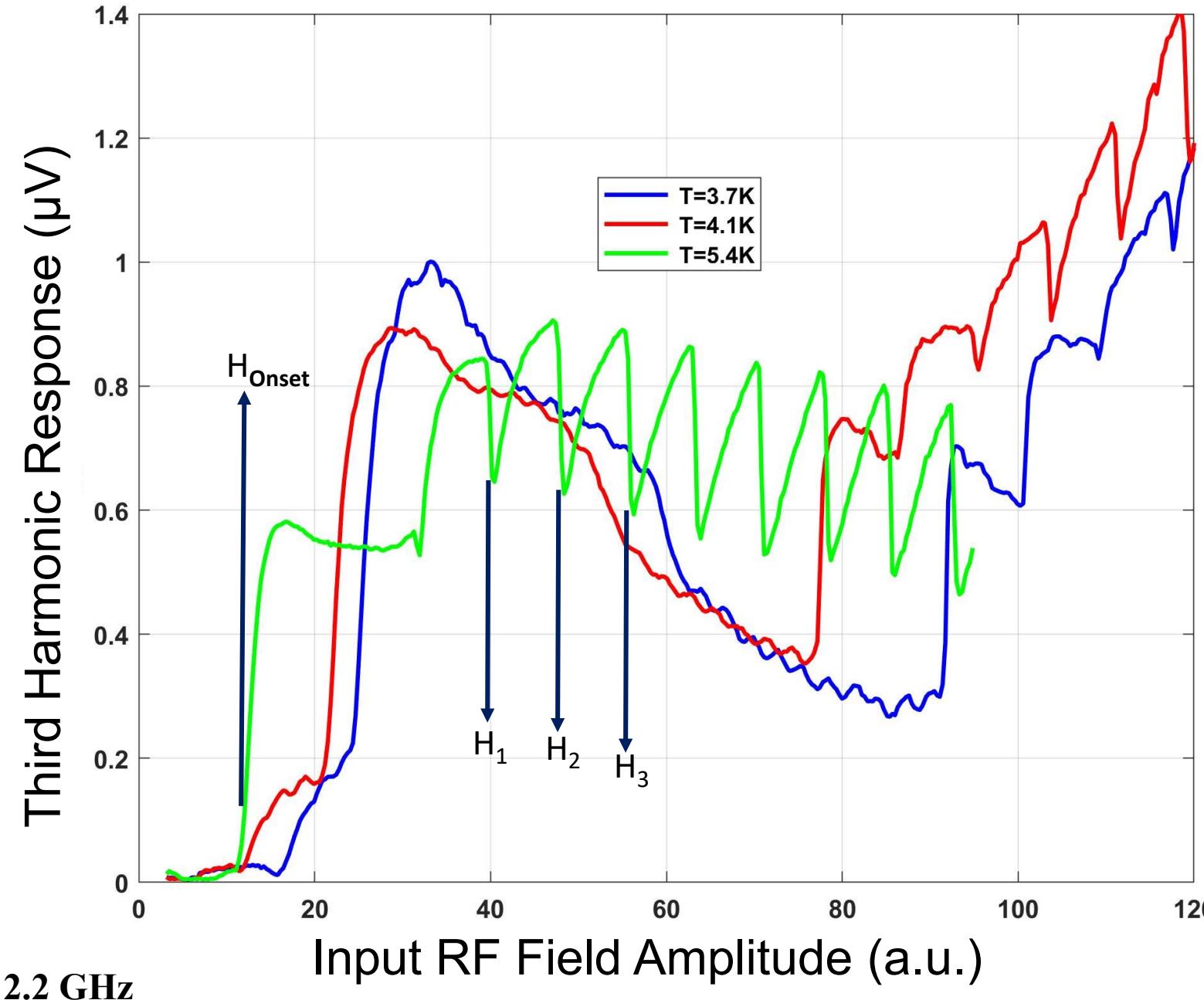


## Point Contact Spectroscopy:

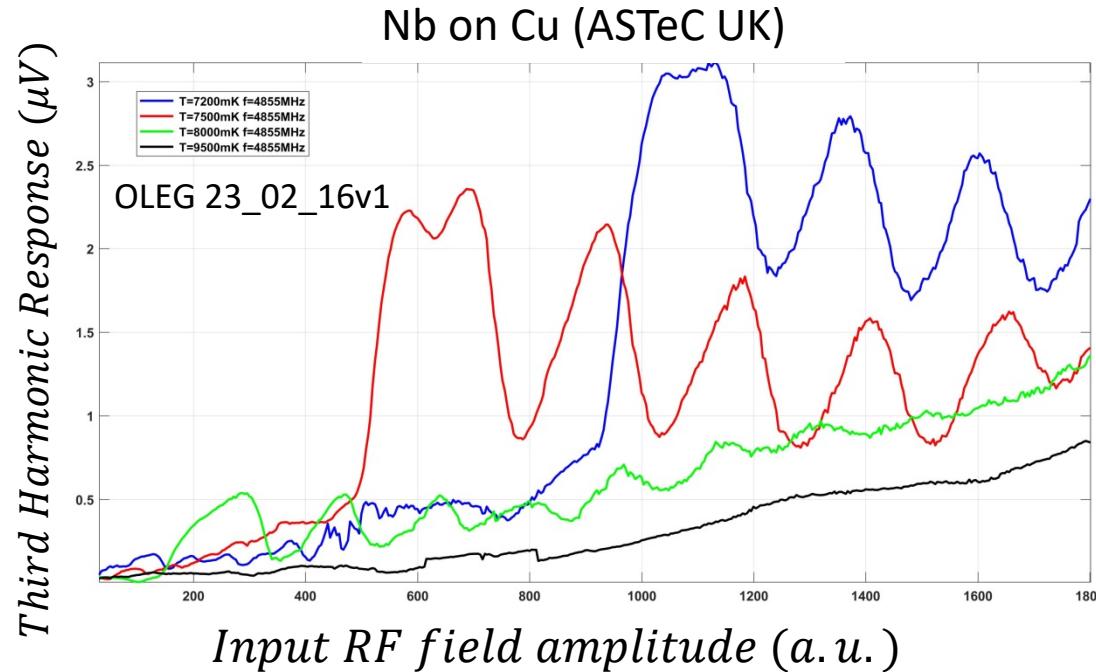
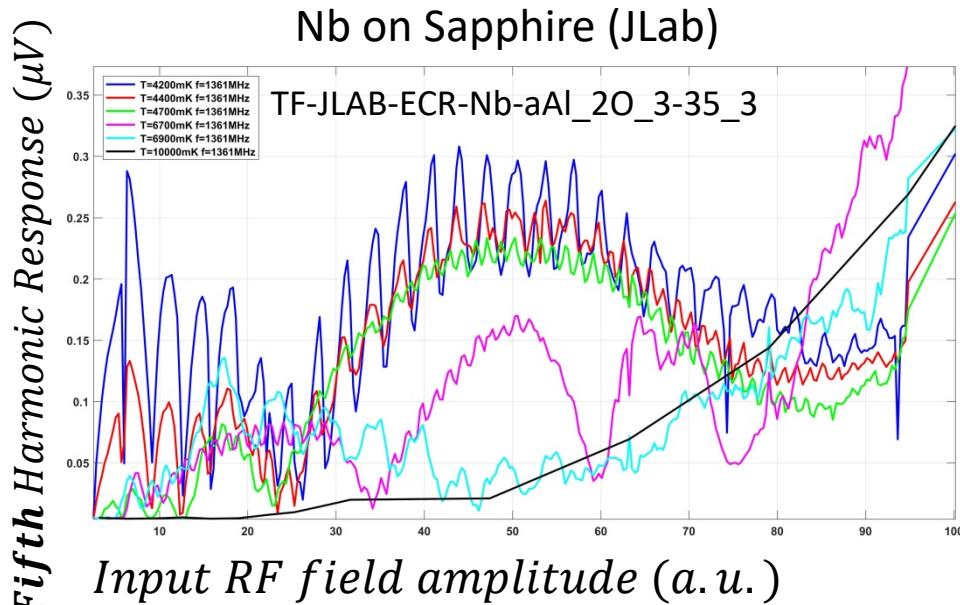
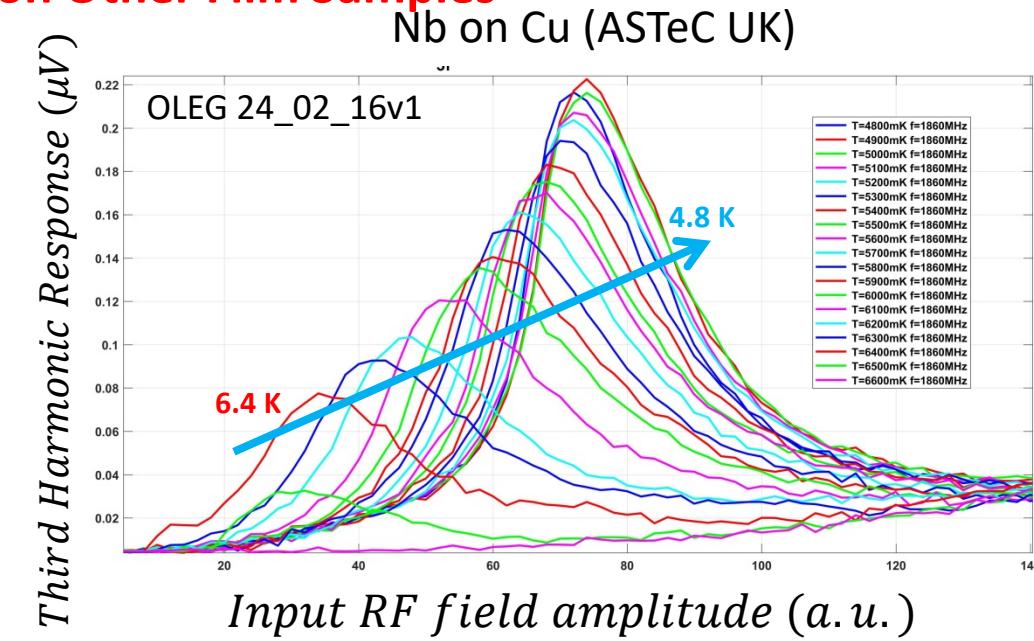
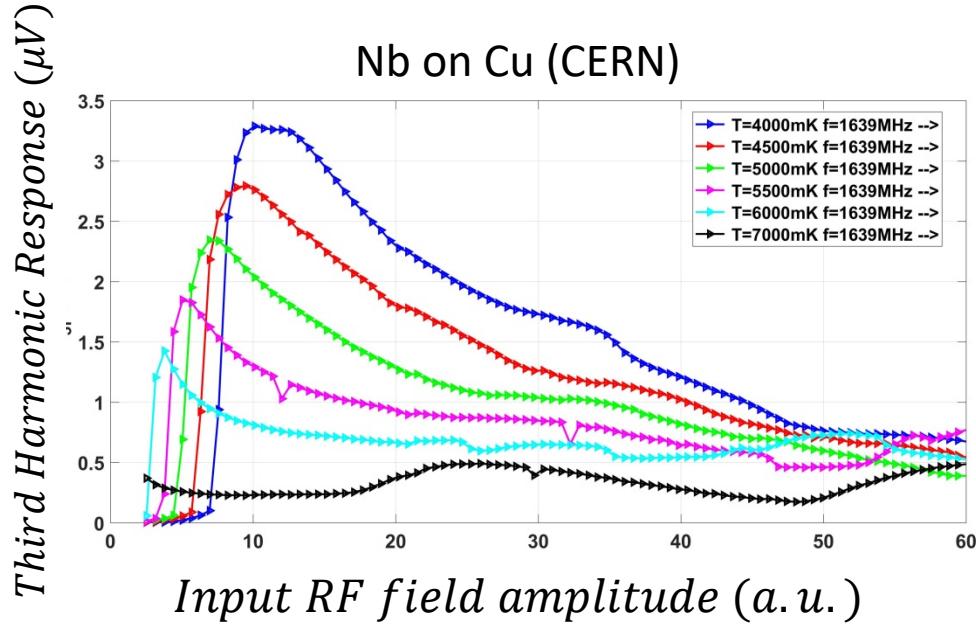
- ✓ Broadened DOS
- ✓ Finite 0-bias conductance (ZBC)
- ✓ Numerous ZBCP



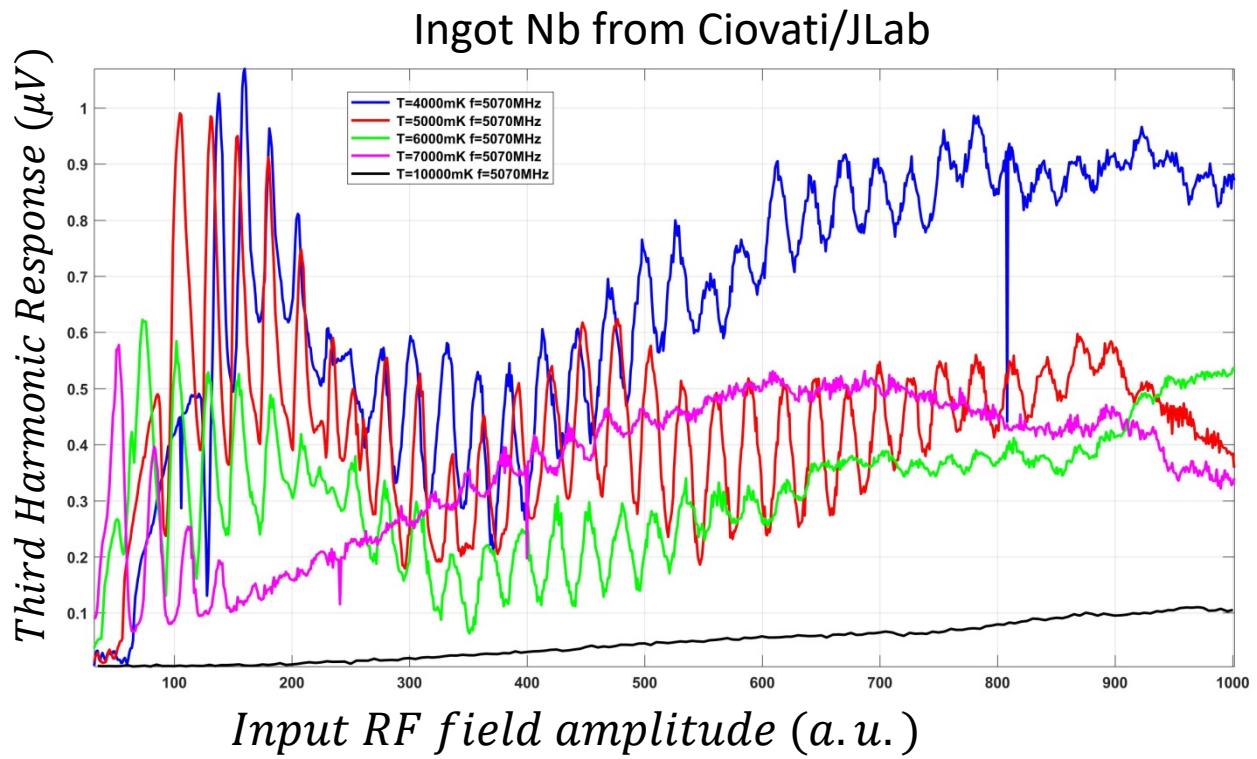
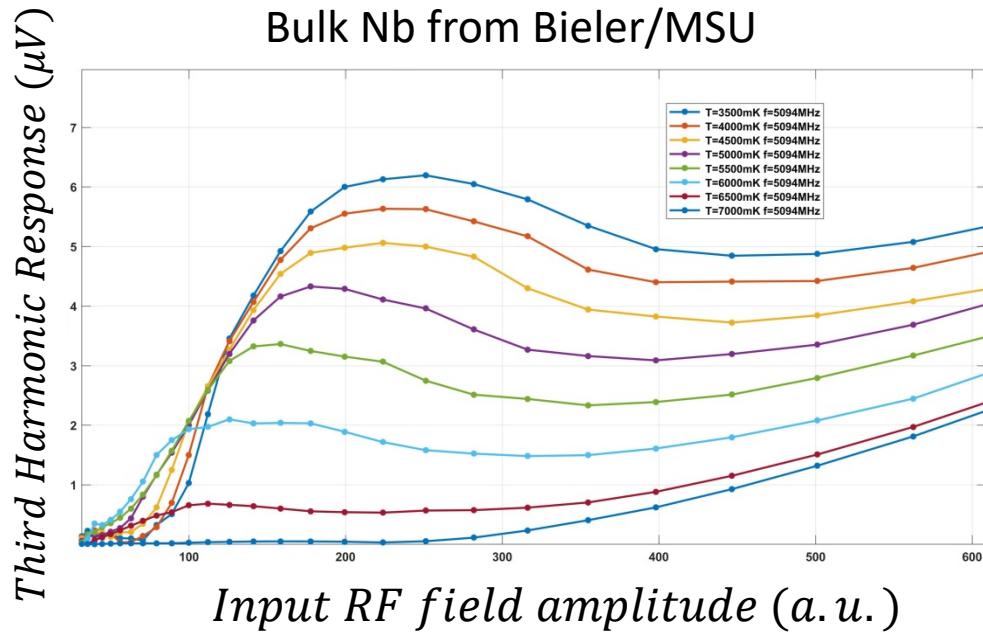
# Nb on Copper samples from CERN



# Similar Results Seen on Other Film Samples



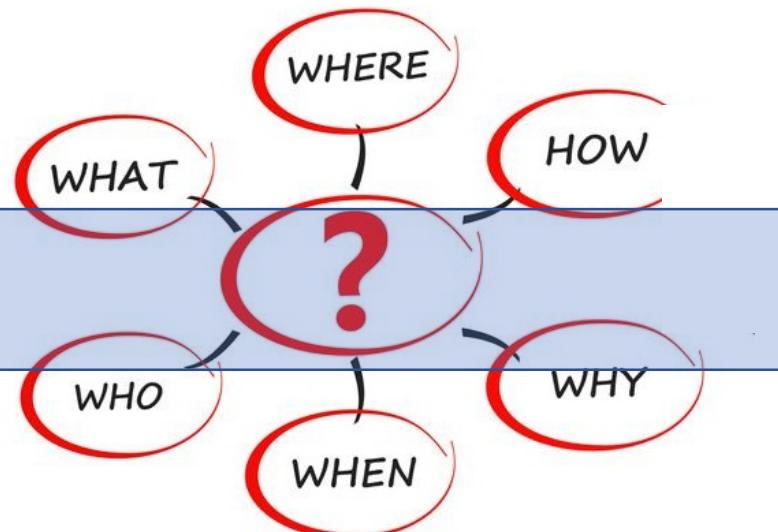
# Similar Results Seen on Bulk Samples



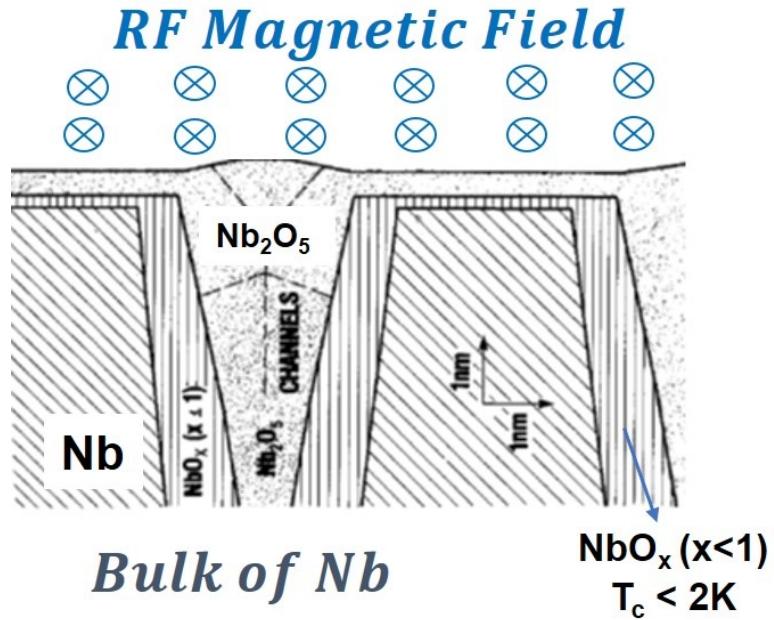
**Bulk and Film samples can show either periodic or non-periodic harmonic response depending on location**

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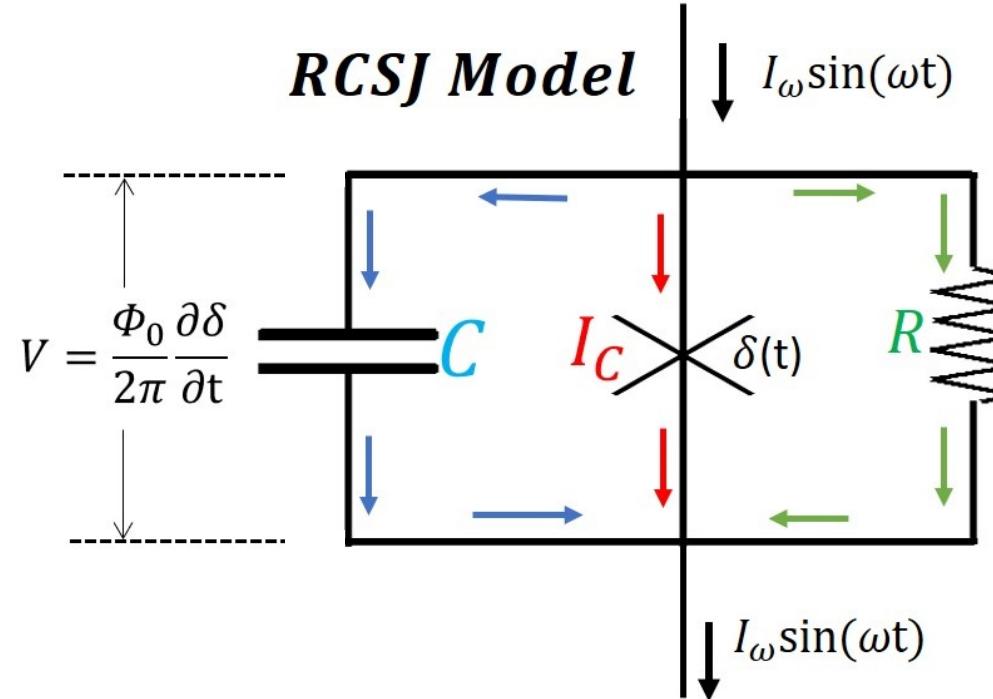


# Current Driven Resistively and Capacitively Shunted Josephson Junctions (RCSJ) model



J. Halbritter, "On the Oxidation and on the Superconductivity of Niobium," J. Appl. Phys. A 43, 1 (1987).

Alternative proposal  
(Kubo and Gurevich, Monday talk)  
S'-I-S layering



$$\frac{\Phi_0 C}{2\pi} \frac{\partial^2 \delta}{\partial t^2} + I_C \sin \delta + \frac{\Phi_0}{2\pi R_n} \frac{\partial \delta}{\partial t} = I_\omega \sin(\omega t)$$

J. McDonald and John R. Clem, "Microwave response and surface impedance of weak links," Phys. Rev. B 56, 14723 (1997).

# Solution to the RCSJ Model

$$\frac{\Phi_0 C}{2\pi} \frac{\partial^2 \delta}{\partial t^2} + I_C \sin \delta + \frac{\Phi_0}{2\pi R_n} \frac{\partial \delta}{\partial t} = I_\omega \sin(\omega t)$$

Short Junction Approximation

All Dimensions Perpendicular to the field  $\ll \lambda_J$

$$(I_C R_n) \sin \delta + \frac{\Phi_0}{2\pi} \frac{\partial \delta}{\partial t} = (I_\omega R_n) \sin(\omega t)$$

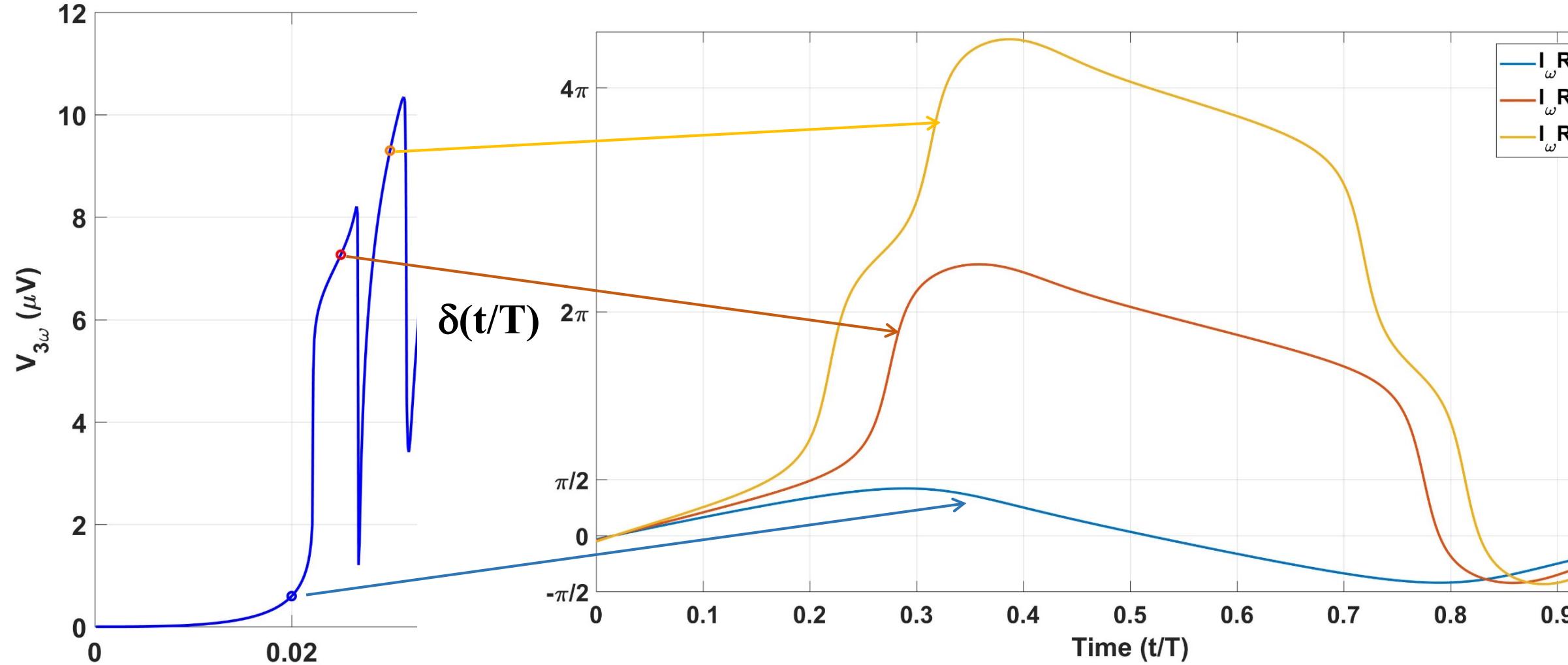
$I_C R_n$  - Fitting Parameter

$I_\omega R_n$  - ScalingFactor \* Input RF Field Amplitude (a.u.)

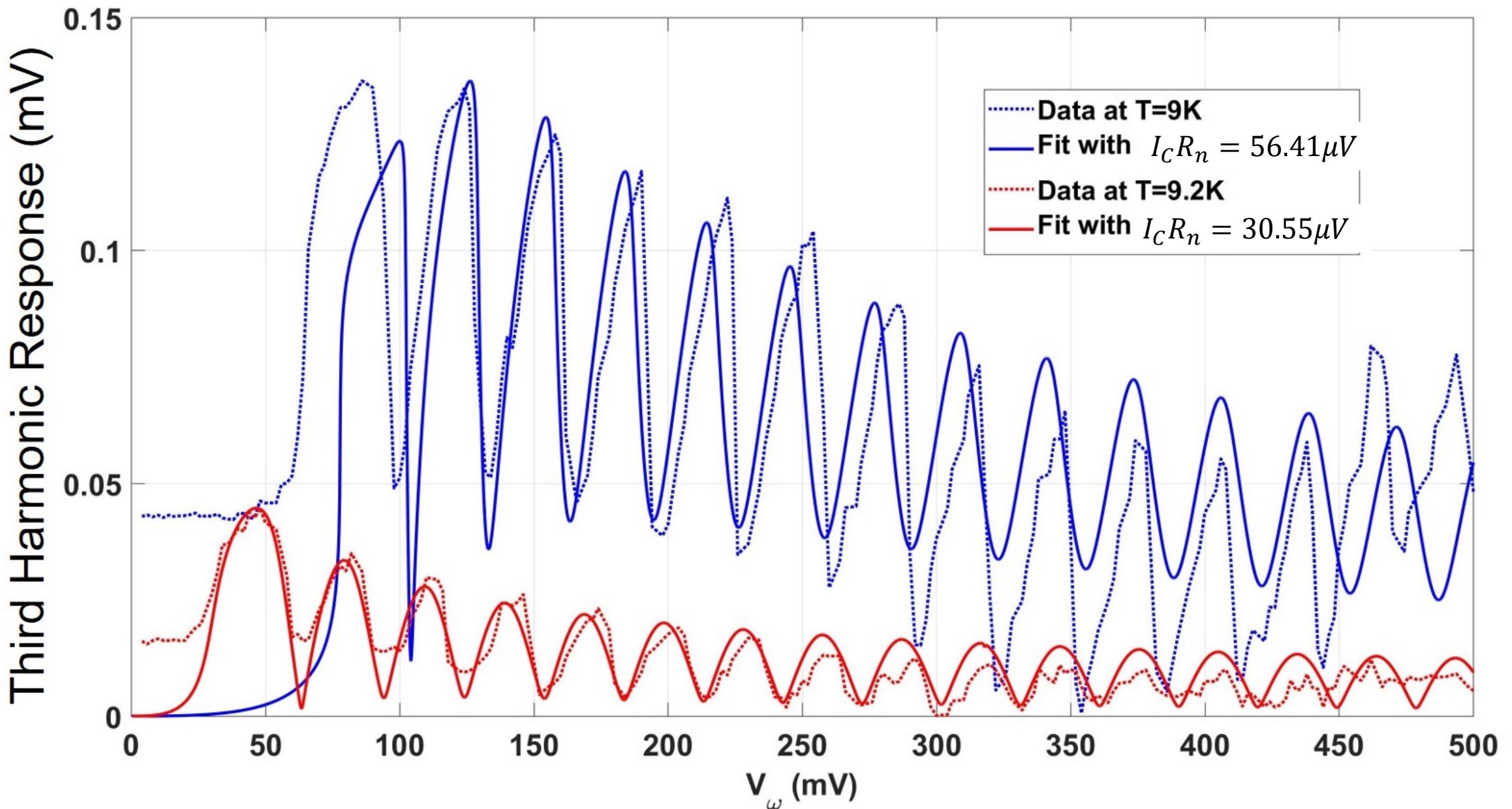
$$\delta(t) \rightarrow V(t) \rightarrow V_{3\omega}$$

# Example Solution to the RCSJ Model

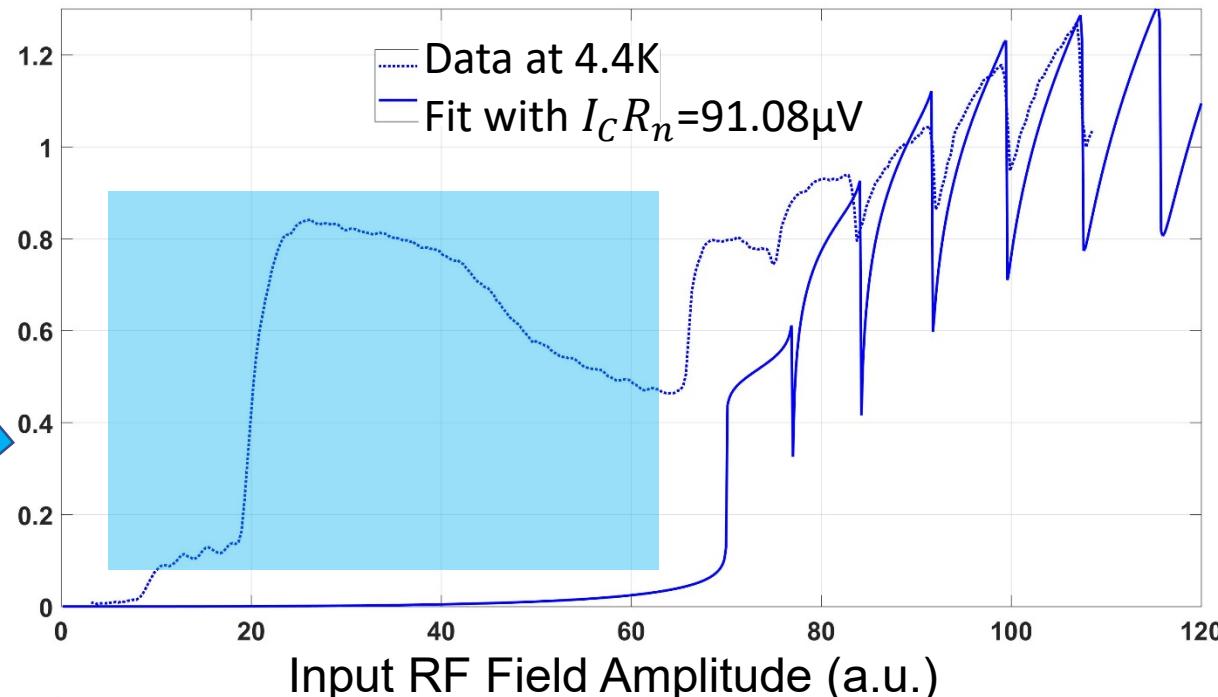
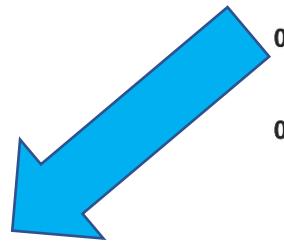
For  $I_C R_n = 20 \mu\text{V}$



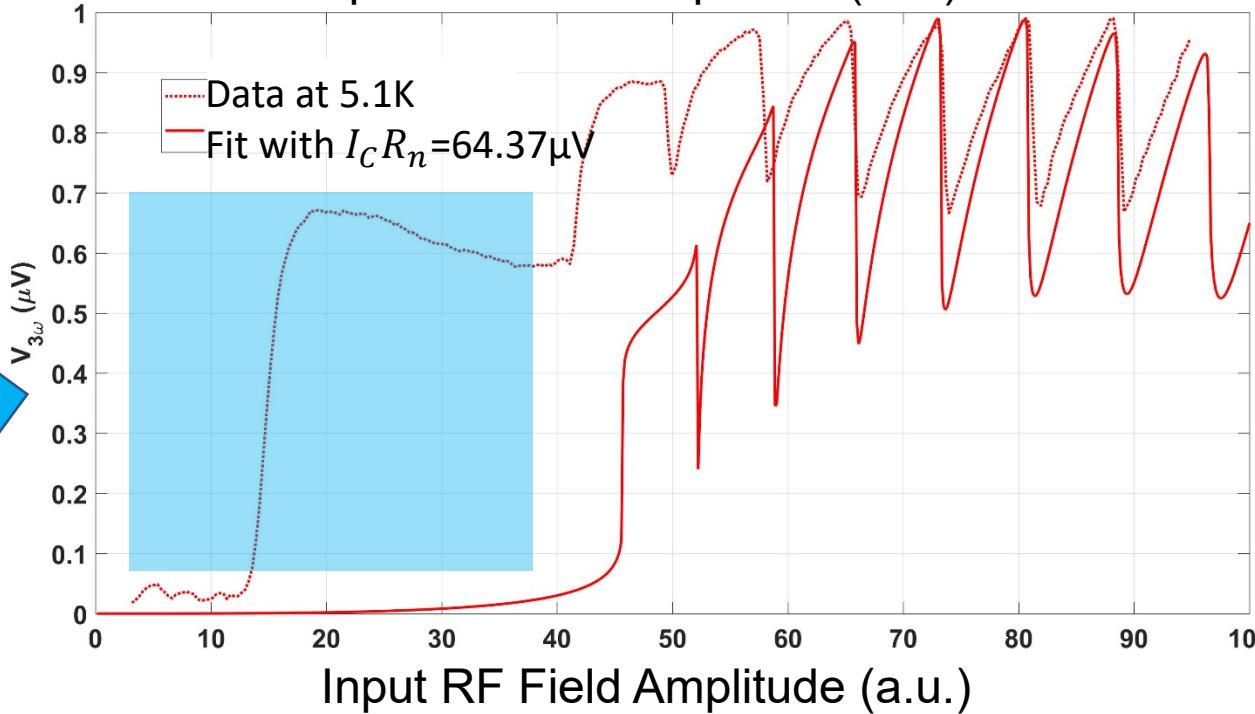
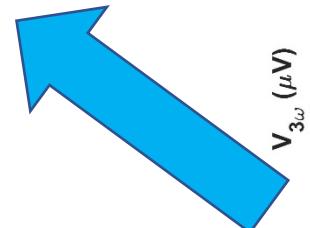
# RCSJ Fit to Bulk Nb Data



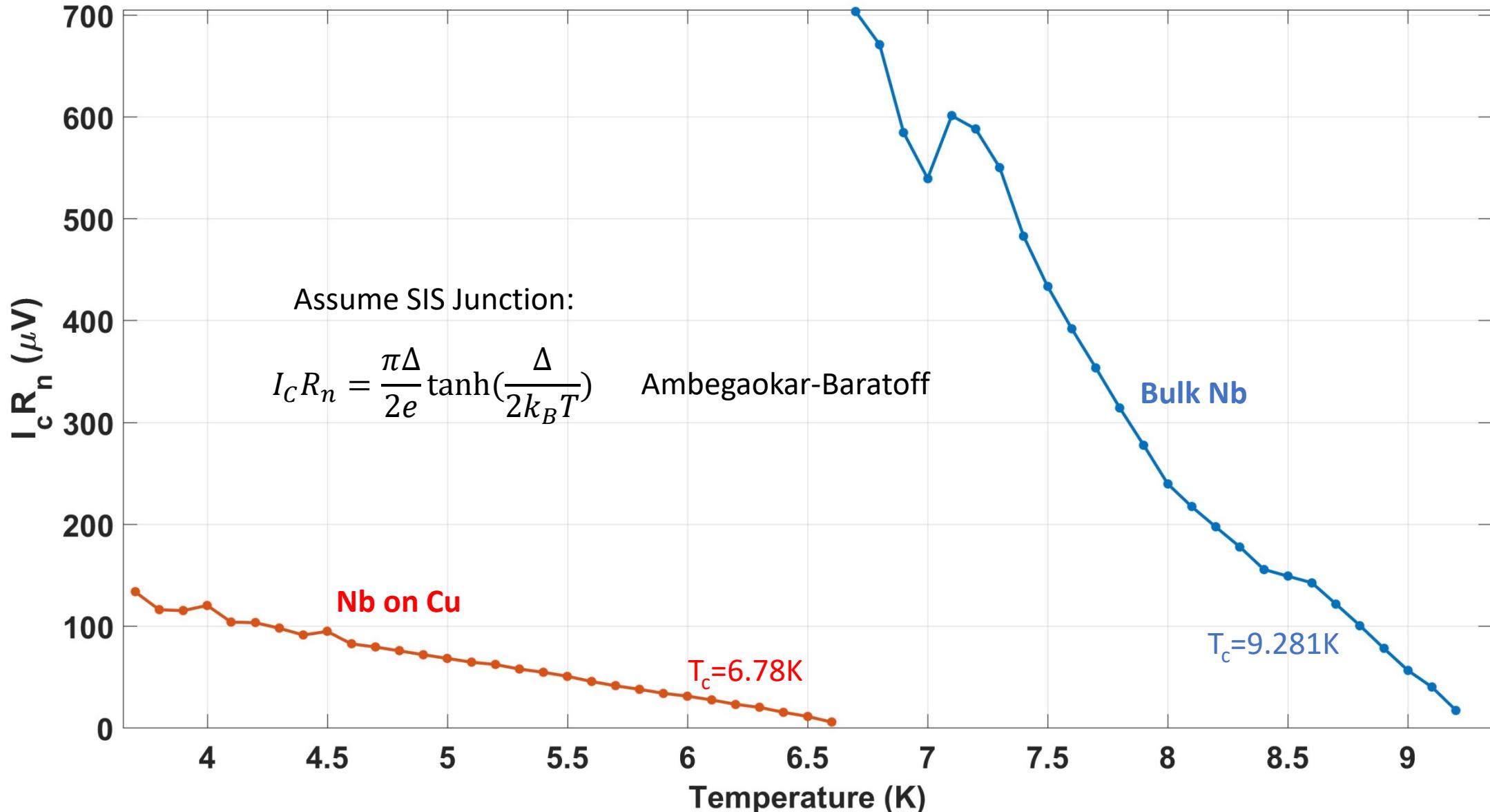
**Nb on Cu Data  
measured at  $f = 2.2$  GHz**



Nonperiodic low input RF field data is not fitted and has a different origin.

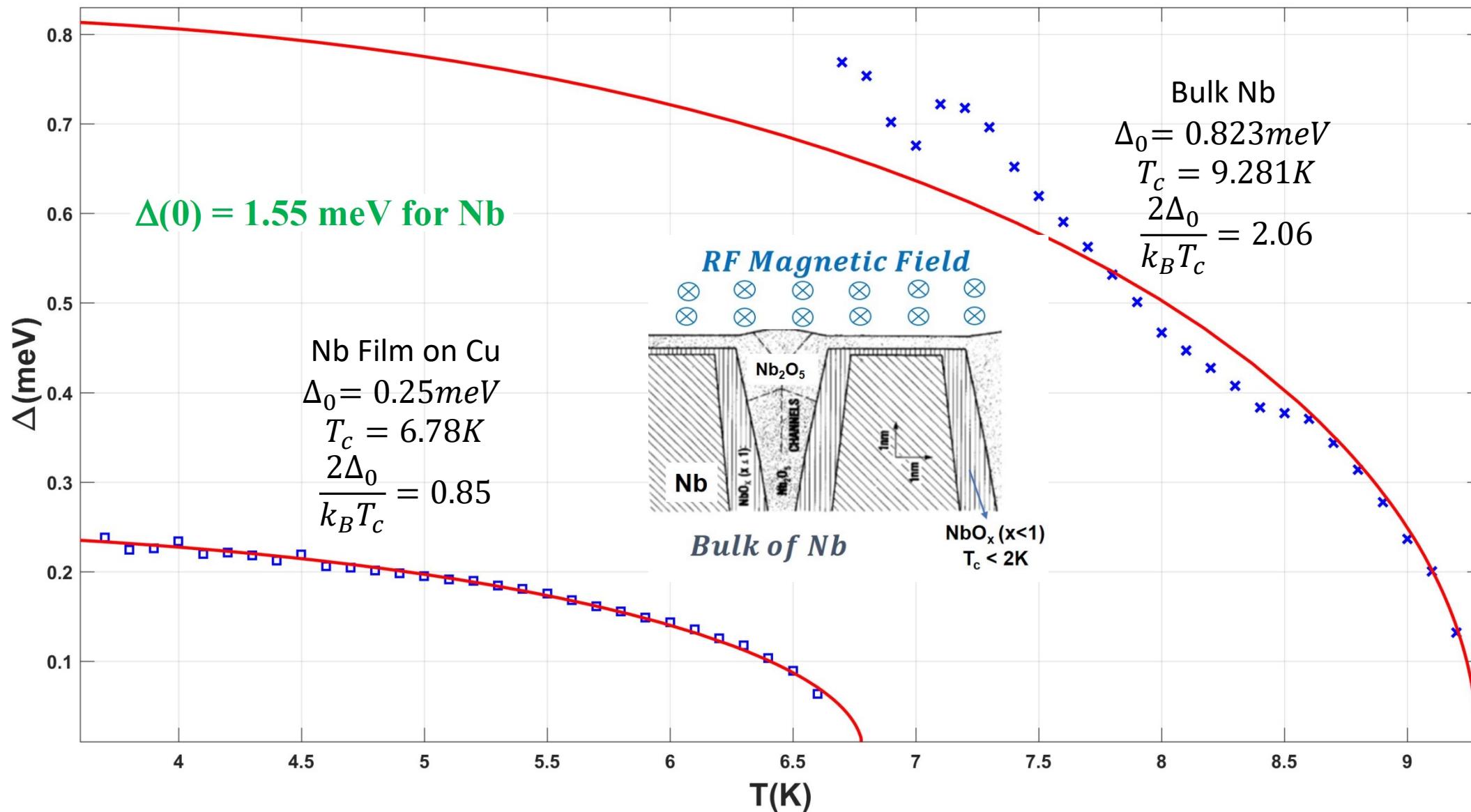


## Junction Critical Current



# Deduced Energy Gap Temperature Dependence

Assuming AB SIS Tunneling in the JJ



# Other Sources of Nonlinear Response

## RF Vortex Entry and Motion in the Superconductor

PHYSICAL REVIEW B 77, 104501 (2008)

Dynamics of vortex penetration, jumpwise instabilities, and nonlinear surface resistance of type-II superconductors in strong rf fields

A. Gurevich<sup>1</sup> and G. Ciovati<sup>2</sup>

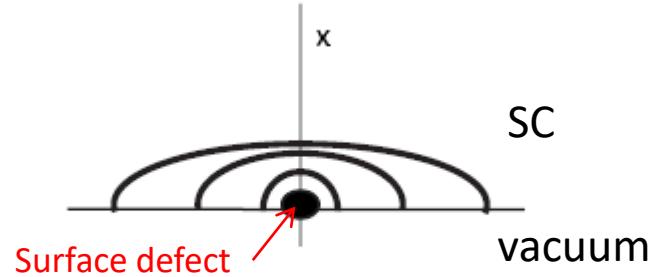
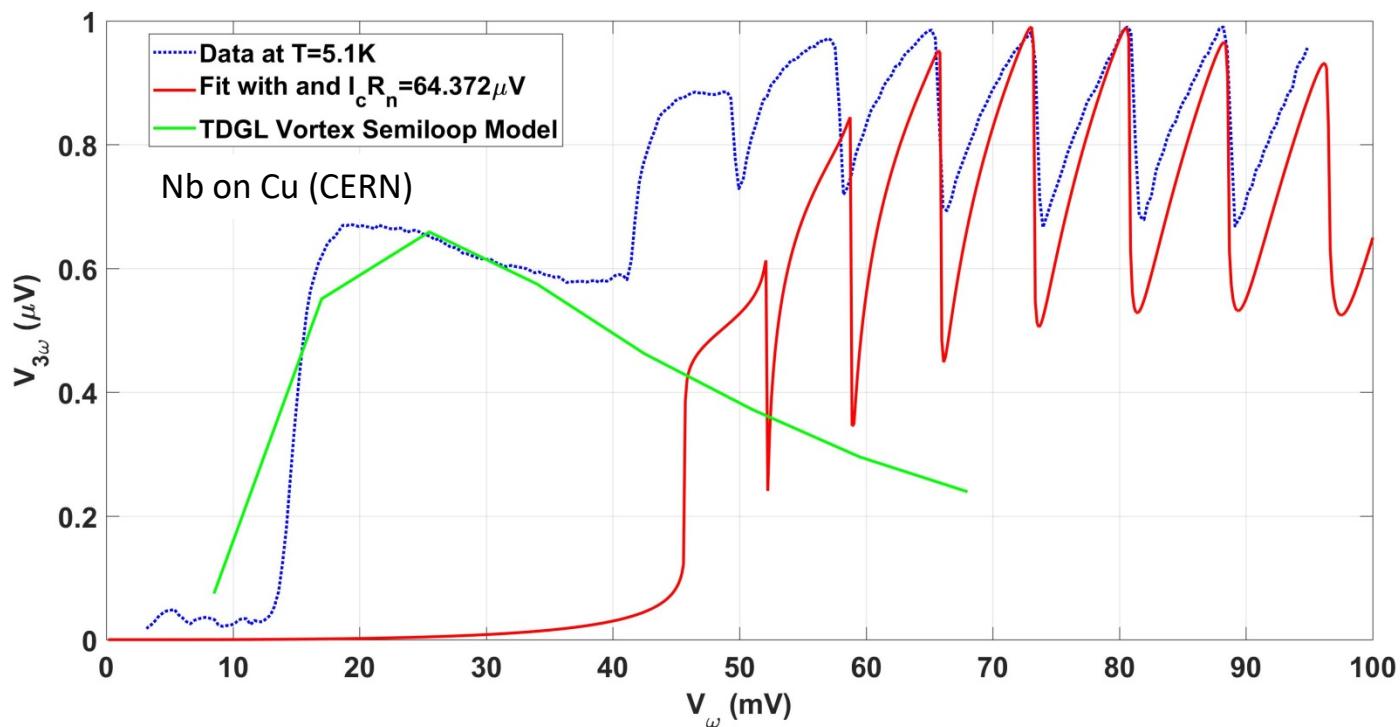


FIG. 2. Snapshots of an expanding vortex semiloop emerging from a surface defect (black dot). The quicker expansion of the loop



# **Normalized TDGL Equations**

$$\eta \frac{\partial \Psi}{\partial t} = - \left( \frac{i}{\kappa} \vec{\nabla} + \kappa \vec{A} \right)^2 \Psi + (1 - T - |\Psi|^2) \Psi$$

$$\vec{\nabla} \times \vec{\nabla} \times \vec{A} = \underbrace{-\sigma \frac{\partial \vec{A}}{\partial t}}_{J_n} - \underbrace{\frac{i}{2\kappa^2} (\Psi^* \vec{\nabla} \Psi - \Psi \vec{\nabla} \Psi^*)}_{J_s} - |\Psi|^2 \vec{A}$$

$$\kappa = \frac{\lambda(0)}{\xi(0)}; \quad \eta = \frac{\tau_{GL}}{\tau_0}; \quad \vec{B} = \vec{\nabla} \times \vec{A}; \quad \vec{E} = - \frac{\partial \vec{A}}{\partial t}; \quad T = \text{Temperature};$$

$$|\Psi|^2 = \begin{cases} 1 & \text{Superconducting State} \\ 0 & \text{Normal State} \end{cases}$$

Length measured in units of  $\lambda(0)$

## TDGL Equations

$$\eta \frac{\partial \Psi}{\partial t} = - \left( \frac{i}{\kappa} \vec{V} + \kappa \vec{A} \right)^2 \Psi + (1 - T - |\Psi|^2) \Psi$$

$$\vec{V} \times \vec{V} \times \vec{A} = -\sigma \frac{\partial \vec{A}}{\partial t} - \frac{i}{2\kappa^2} (\Psi^* \vec{V} \Psi - \Psi \vec{V} \Psi^*) - |\Psi|^2 \vec{A}$$

$J_n$

$J_s$

**T = 0,  $\kappa = 1, \eta = 1$**

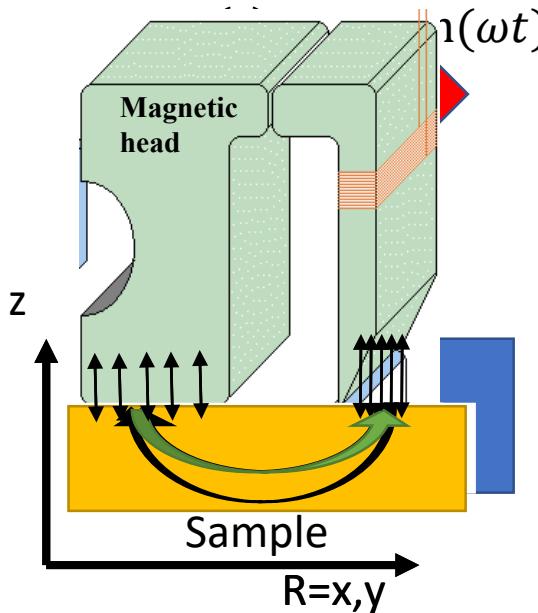
**Dipole Height = 10  $\lambda$**

**Max surface field = 0.8  $B_{c2}$**

**Frequency  $\approx 500$  MHz**

**NO DEFECTS**

**Side View:**



Sample Surface, View from Top

Time=0 s

Fully SC

$|\Psi|^2$

1

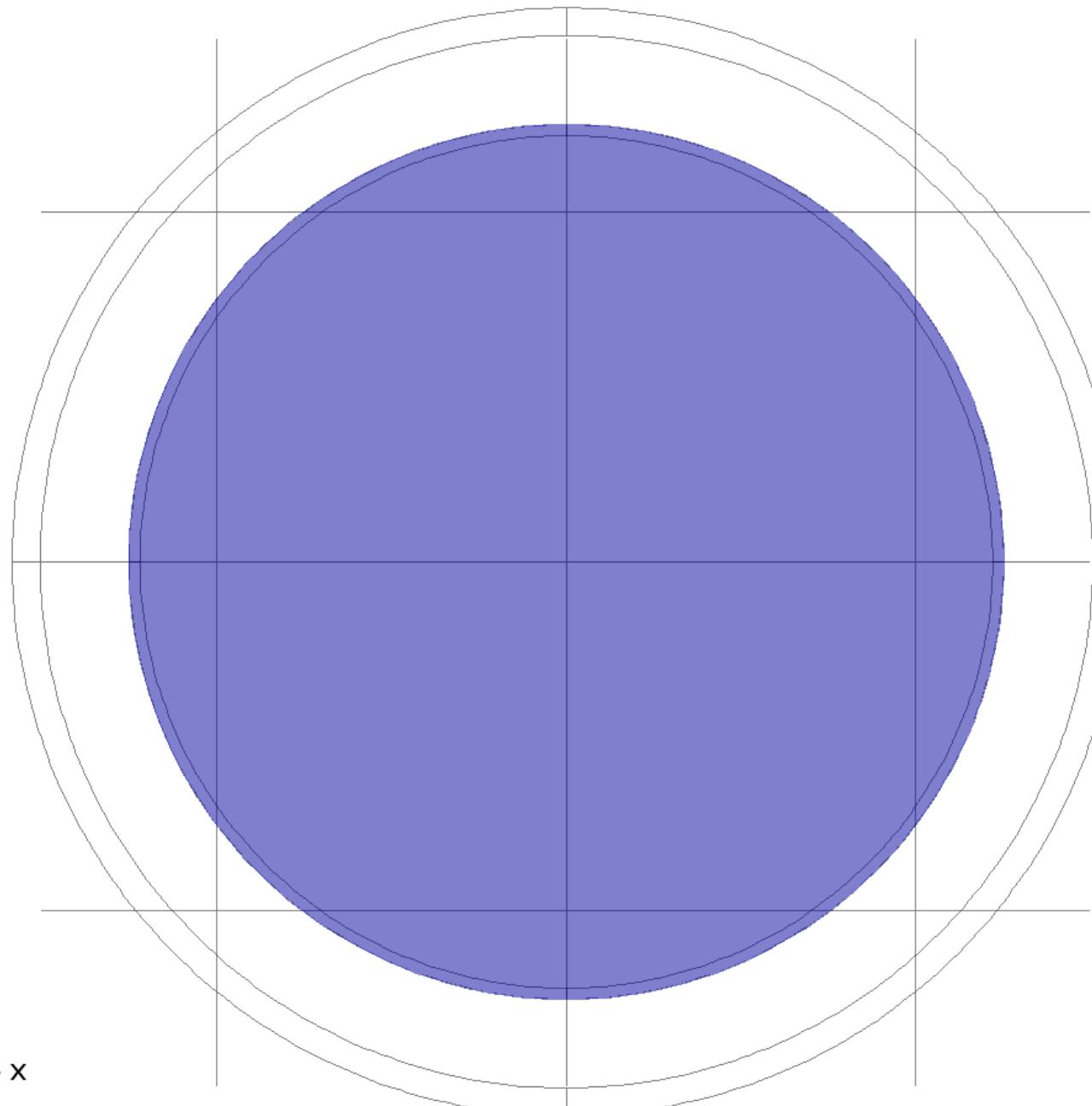
10

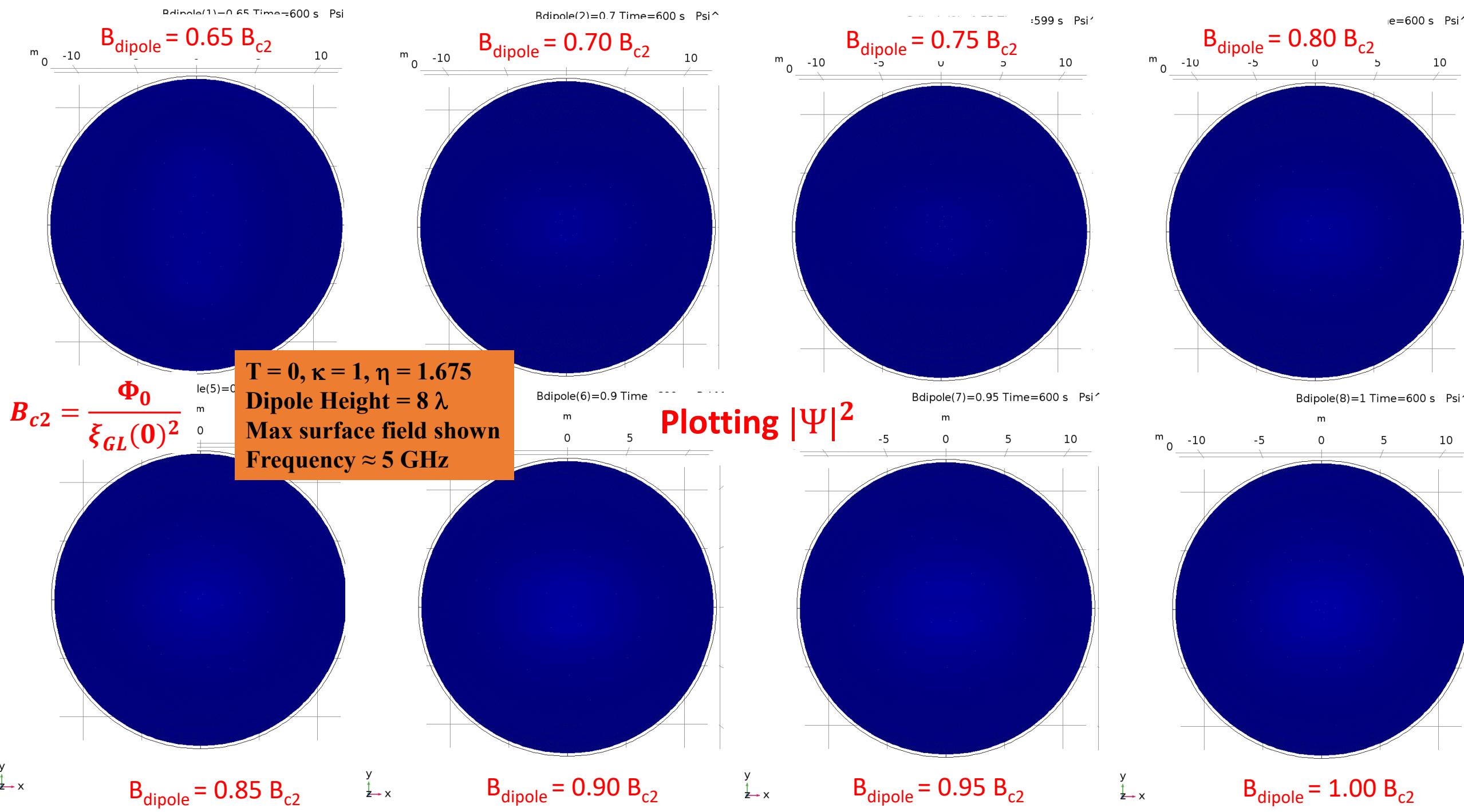
0 m

-10

Fully  
Normal

y  
z  
x

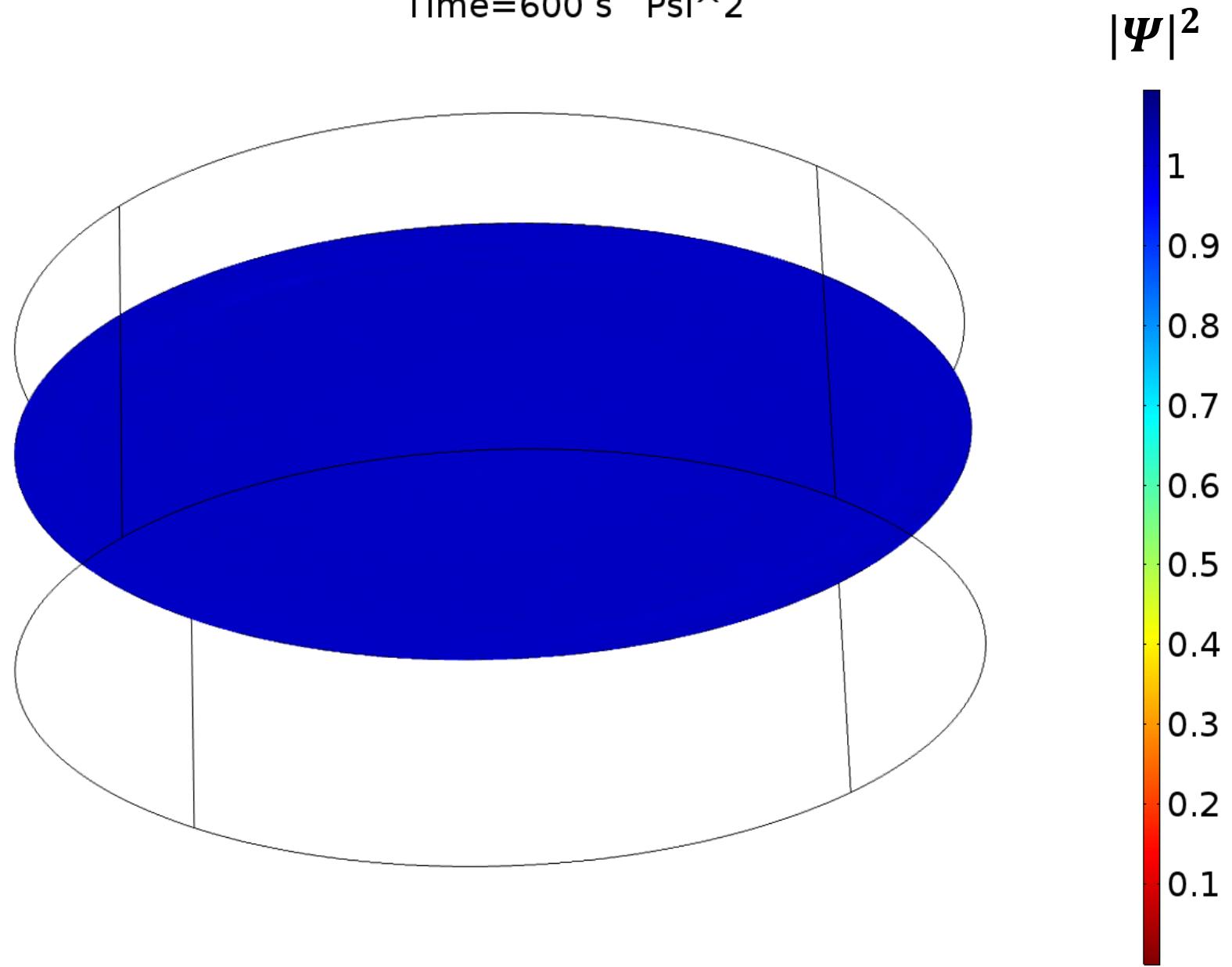




# Horizontal RF Dipole Above Superconductor

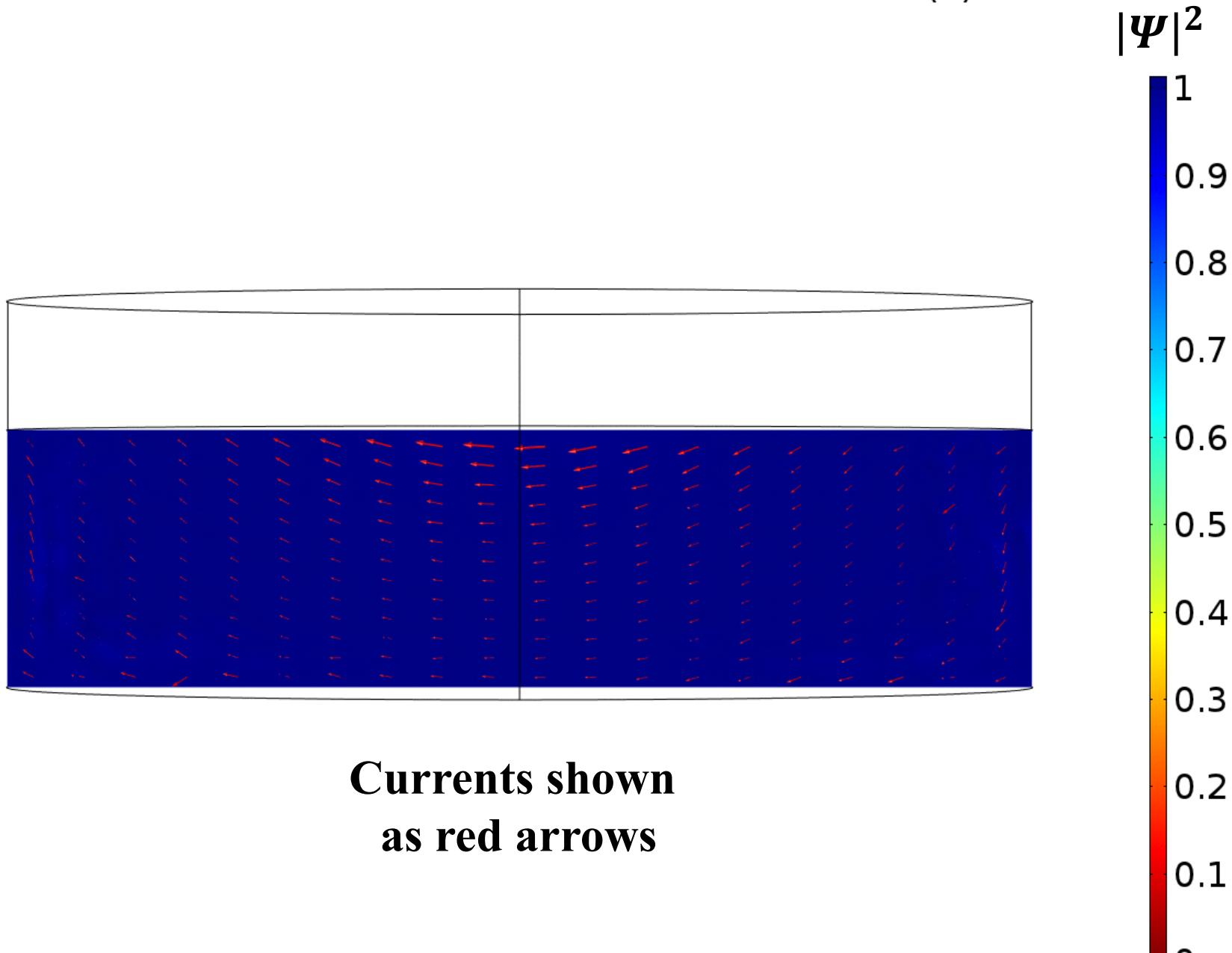
Time=600 s Psi^2

$\kappa = 1$   
 $\eta = 1.675$   
 $T = 0$   
 $H_{\text{dipole}} = 8 \lambda$   
 $B_{\text{dipole}} = 0.75 B_{c2}$   
Period =  $200 \tau_0$   
Frequency  $\approx 5 \text{ GHz}$   
NO DEFECTS



# Horizontal RF Dipole Above Superconductor

Time=600 s Arrow Volume: Slice: Psi^2 (1)



# TDGL Harmonic Response May Explain Onset of $V_{3f}$ in Nb Films

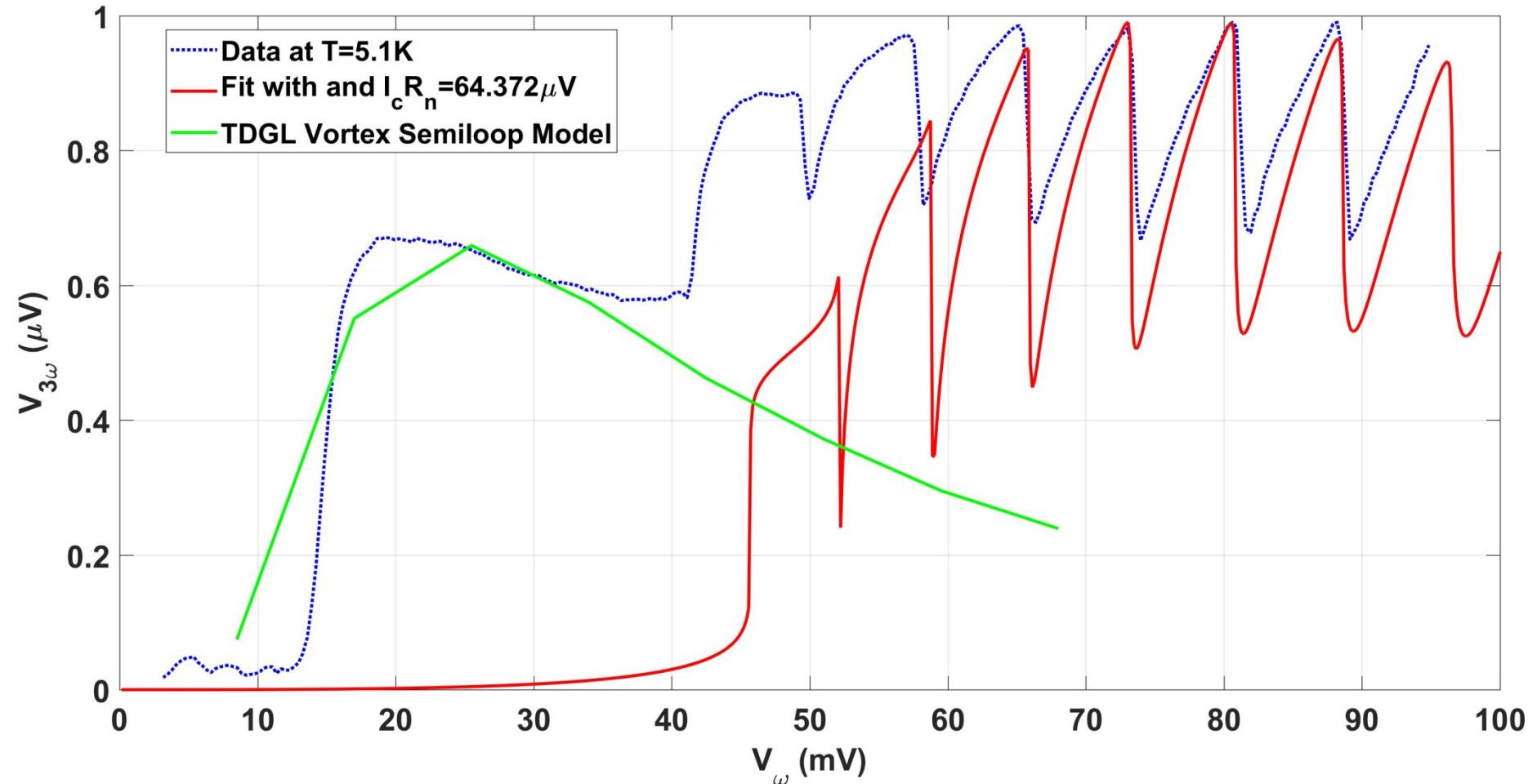
$T = 8.5 \text{ K}$ ,  $\kappa = 1$ ,  $\eta = 1.675$

Dipole Height =  $12 \lambda$

Max surface field =  $0.05 - 0.6 B_{c2}$

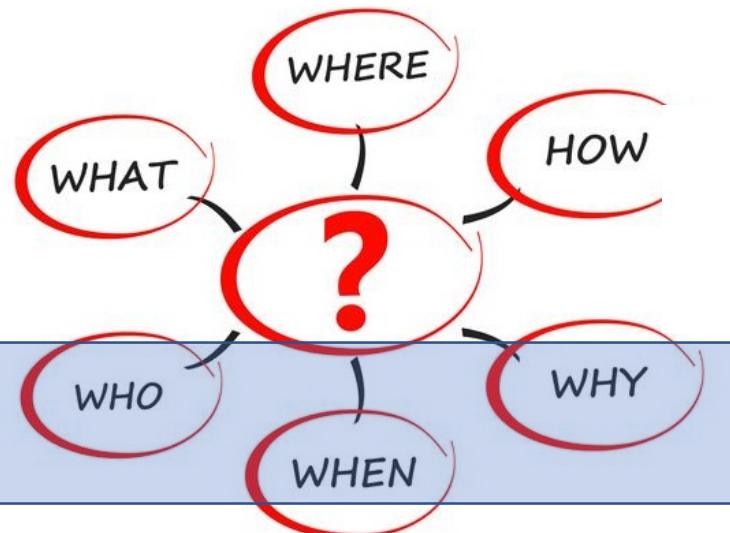
Period =  $200 \tau_0$

Frequency  $\approx 5 \text{ GHz}$



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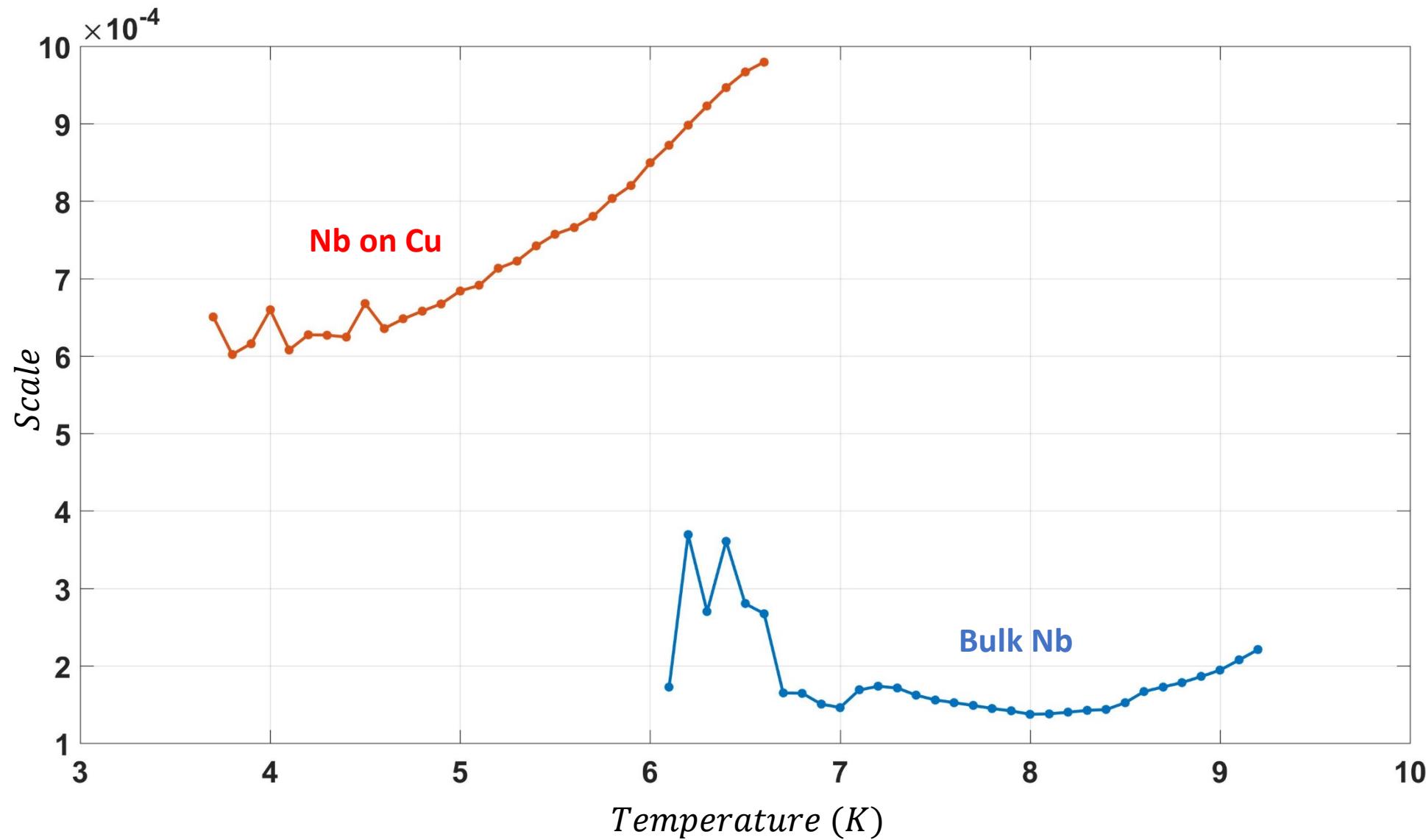
# Summary

- We validate the existence of weak-links on the surface of Nb
- Magnetic Microwave Microscopy can be used to extract local  $T_c$  and Effective BCS Gap at the weak-link

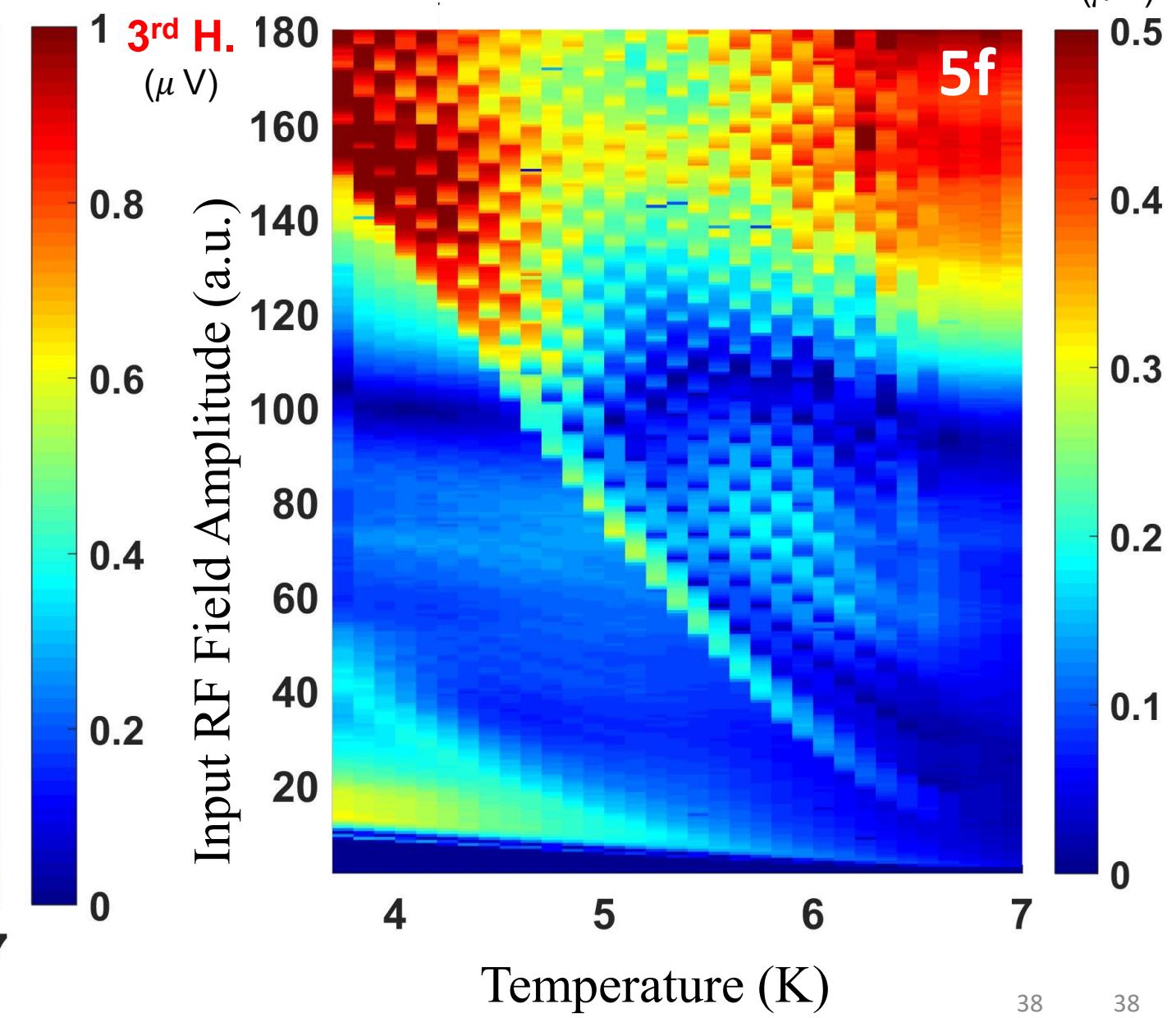
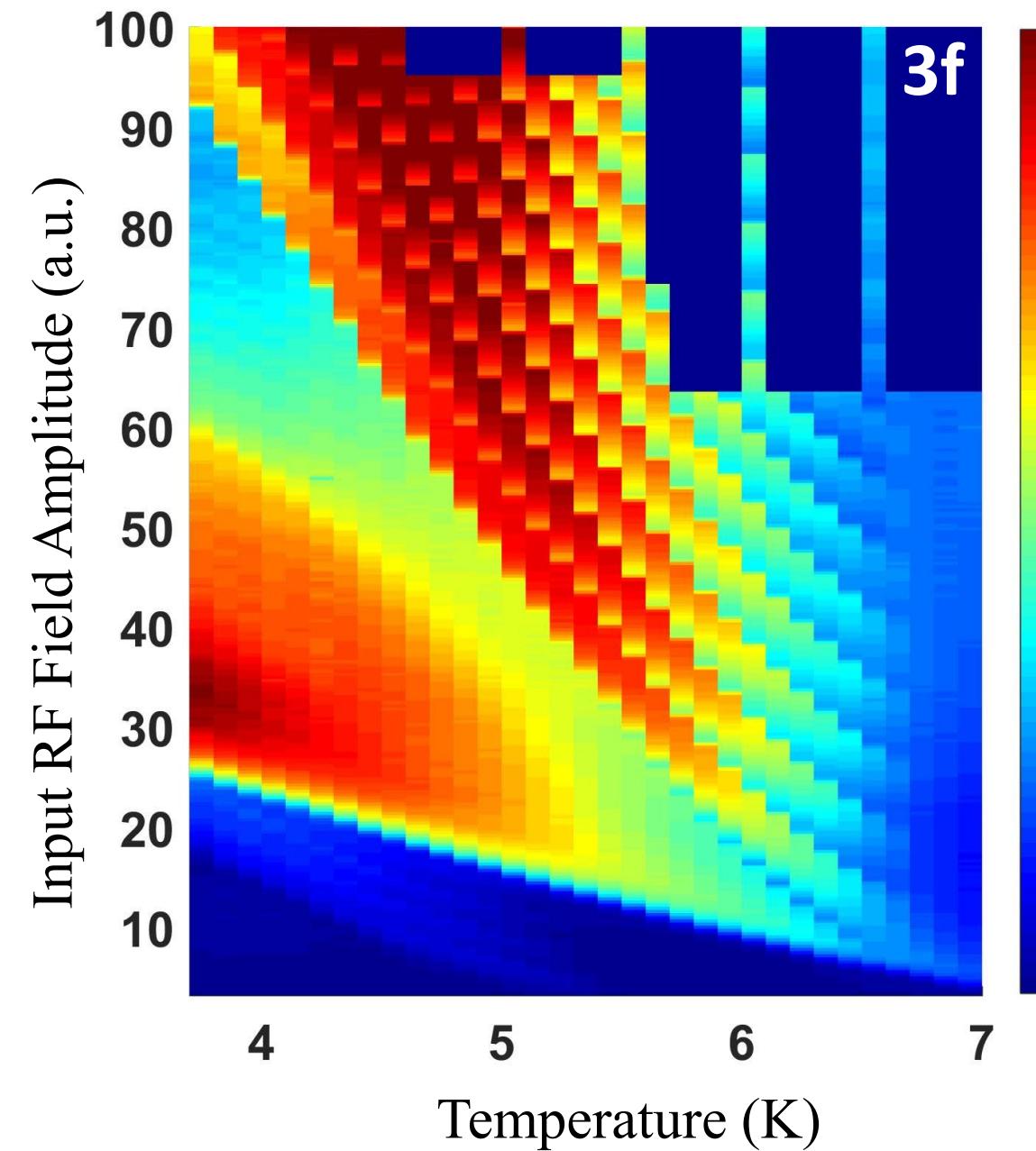
## Future Work

- TDGL Simulations are being performed to study “pedestal” data on thin films
- Raster Scanning over known defect while imaging onset field
- Measurement of multilayer/single layer samples

**fin**



# Periodicity of Nb Thin Film Harmonics



5<sup>th</sup> H.  
( $\mu\text{V}$ )

0.5

0.4

0.3

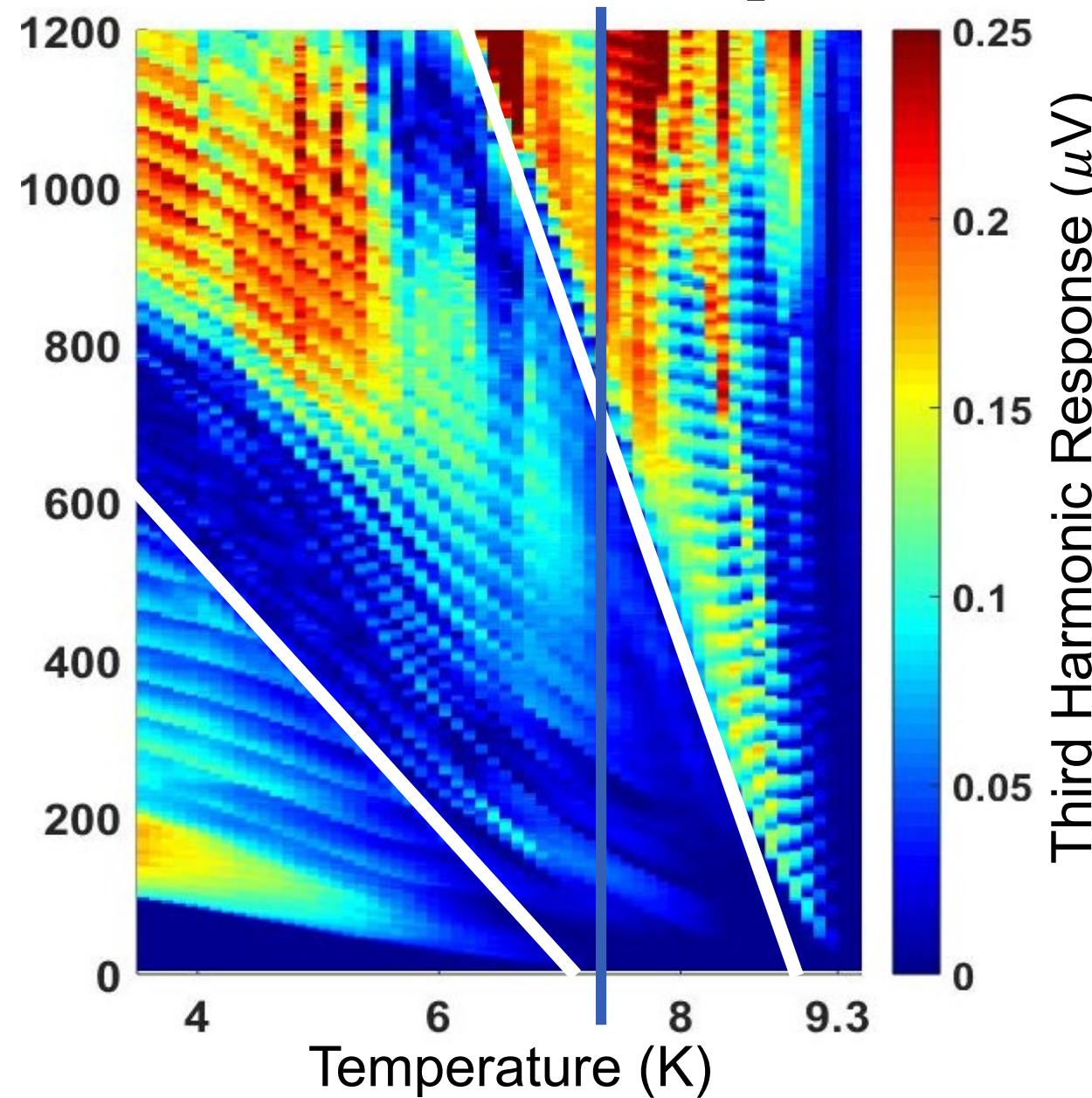
0.2

0.1

0

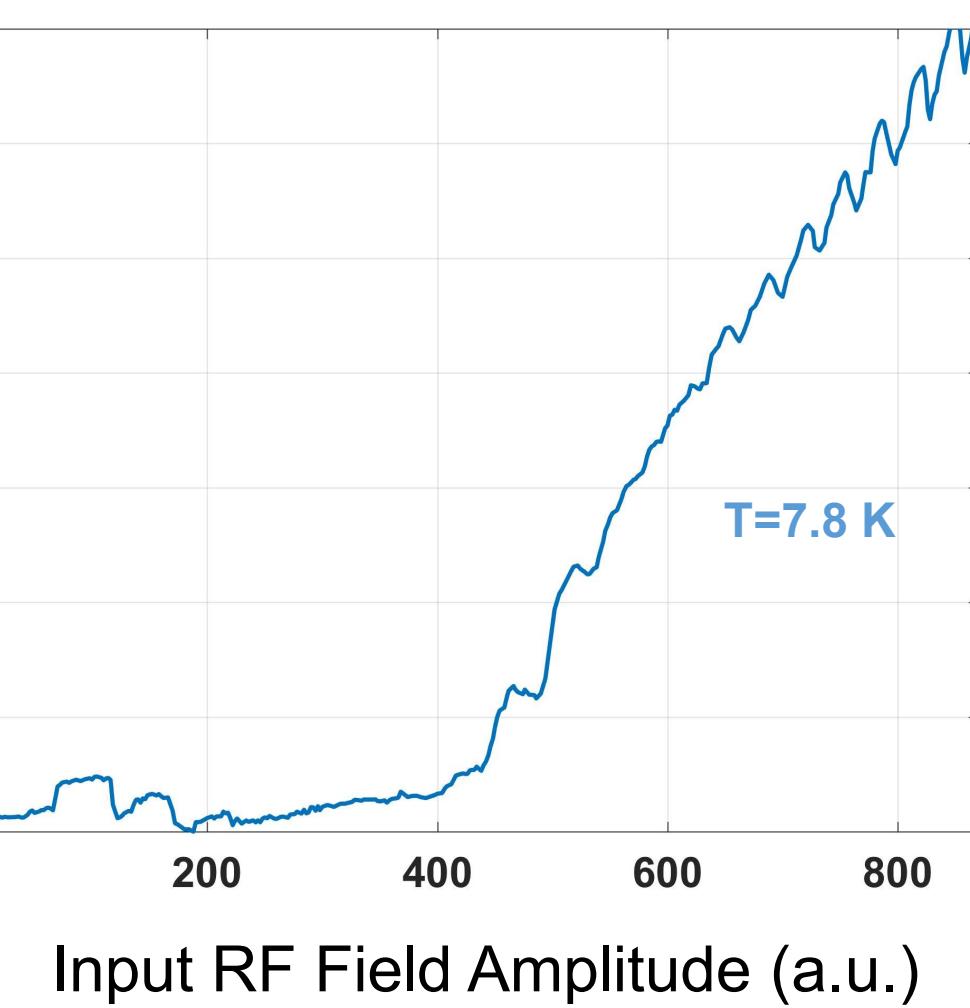
# Bulk Nb Data: Multiple Periodicity in Harmonic Response

Input RF Field Amplitude (a.u.)



Temperature (K)

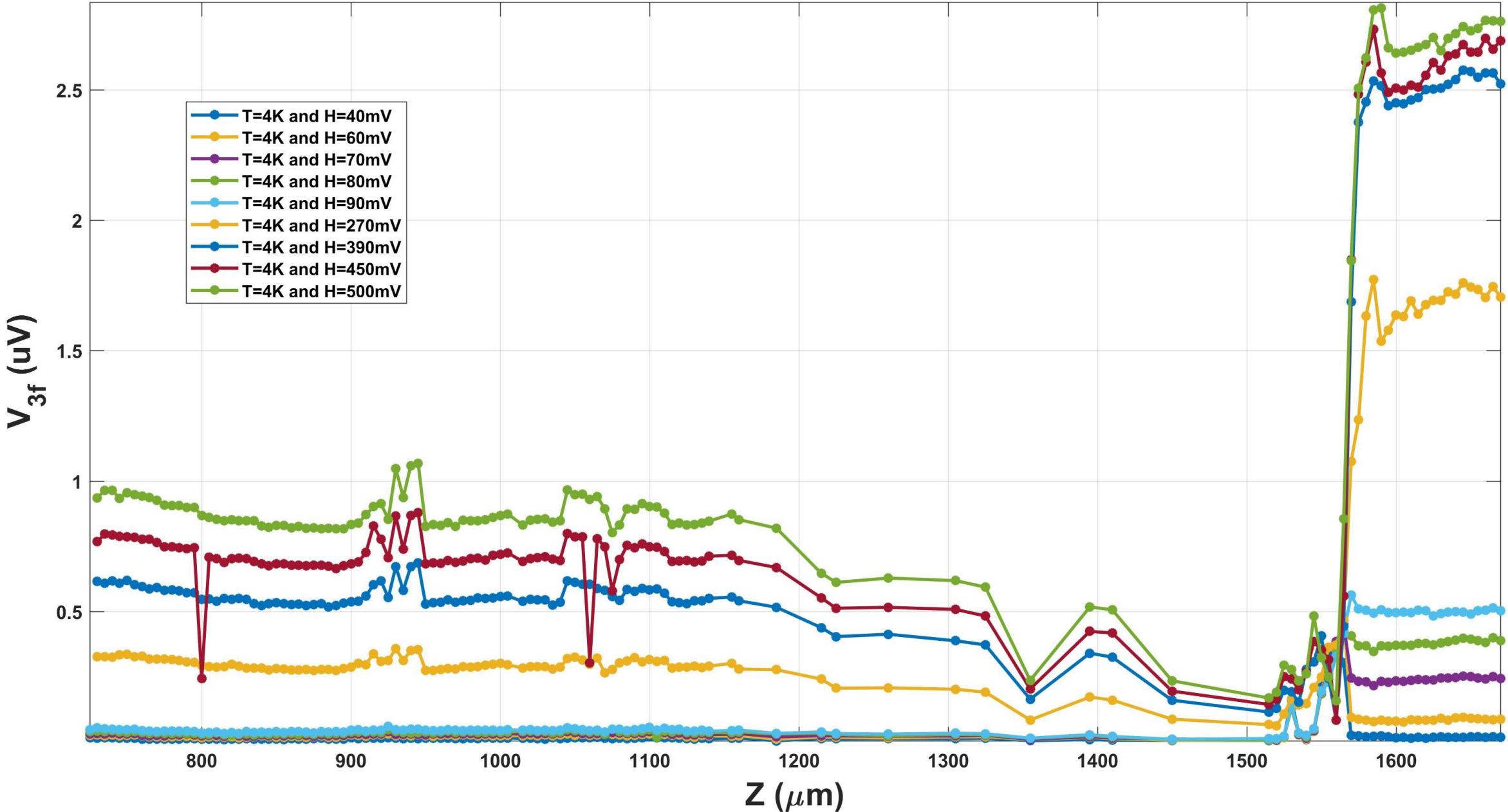
Third Harmonic Response ( $\mu\text{V}$ )

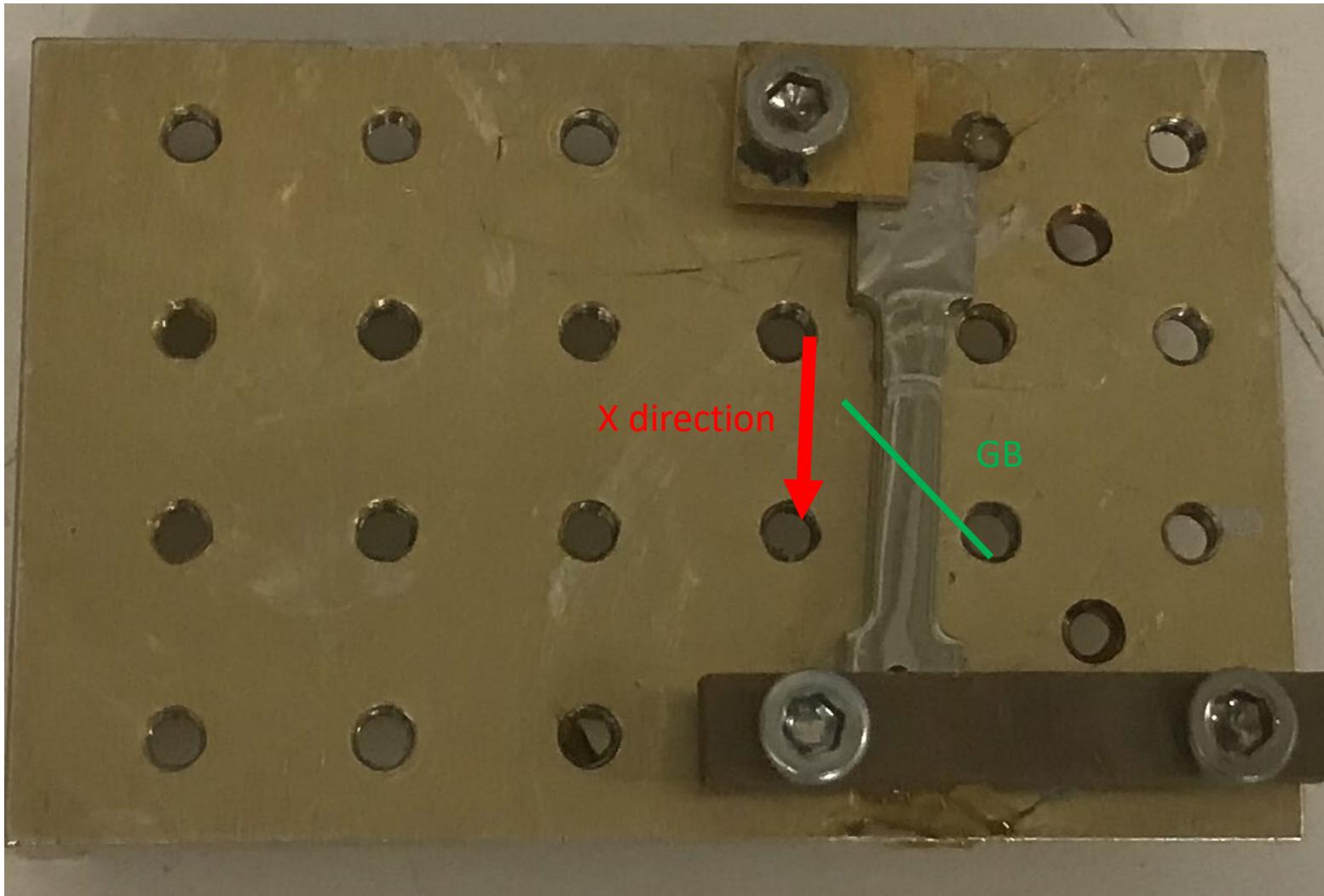


Input RF Field Amplitude (a.u.)

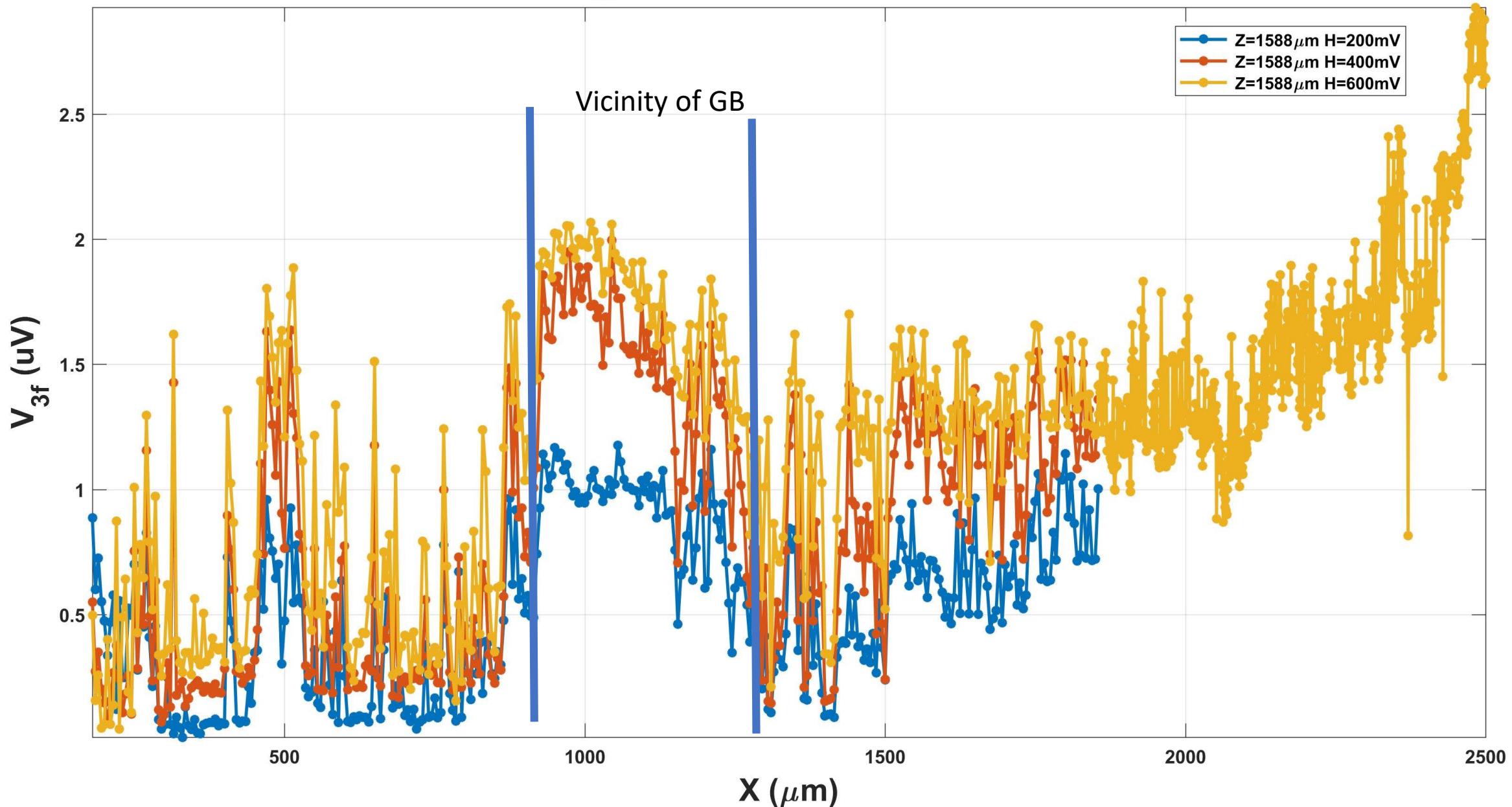
$T = 7.8 \text{ K}$

# $V_{3f}$ vsZ setpoint Combined





# $V_{3f}$ vs X setpoint (Combined)

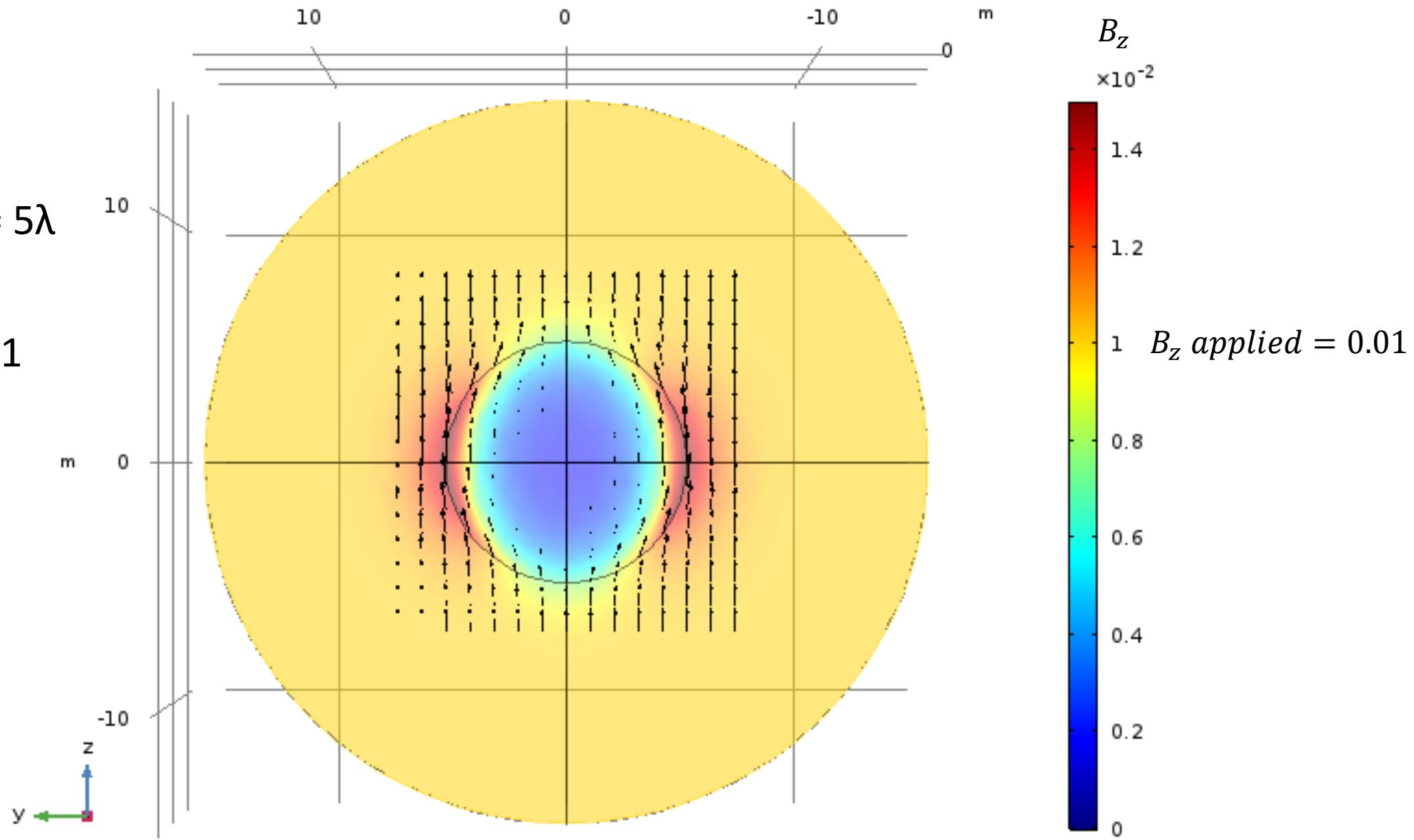


# Superconducting Sphere in a Uniform Static Magnetic Field

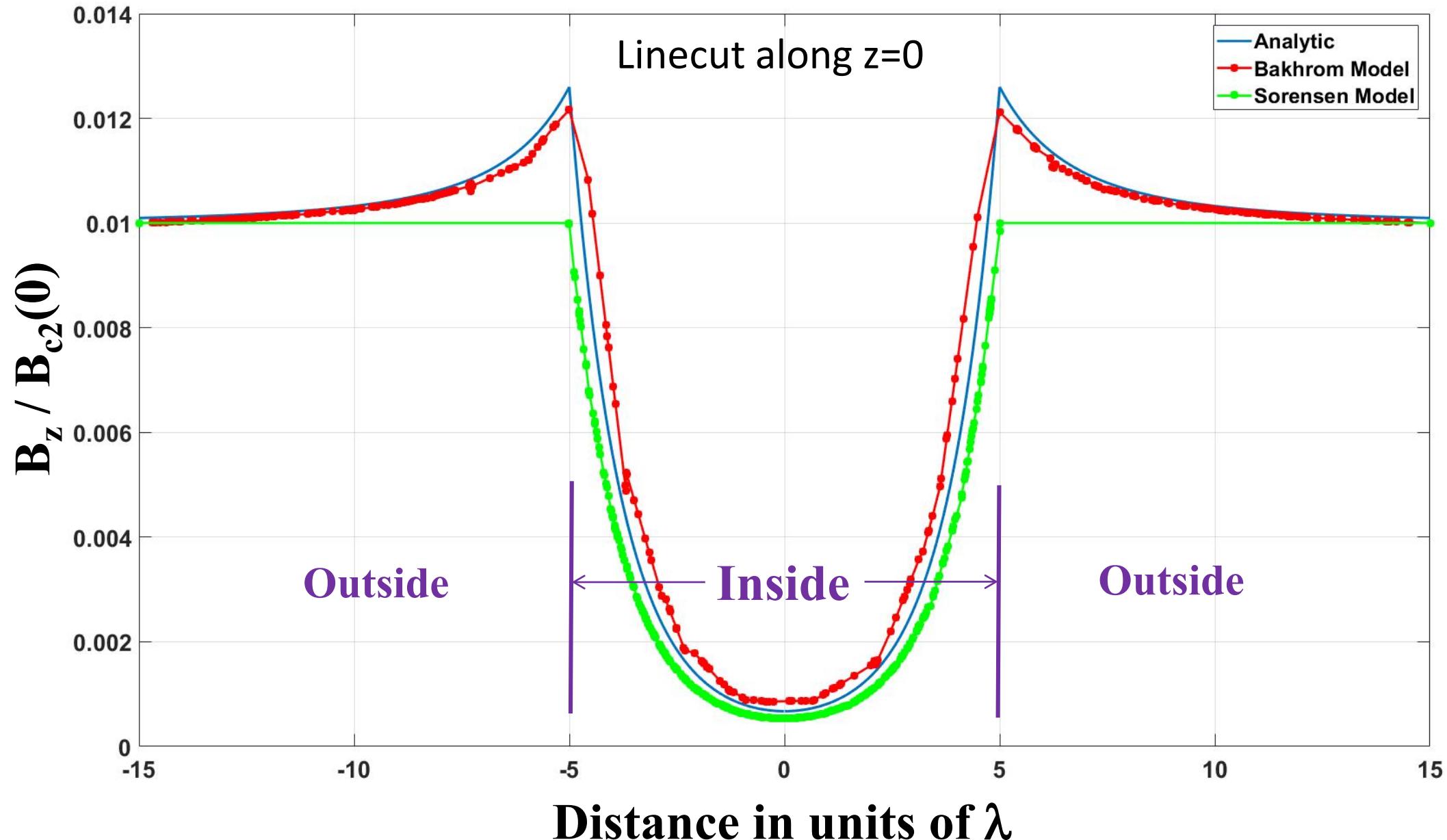
Sphere Radius =  $5\lambda$

$\kappa = 1, T = 0;$

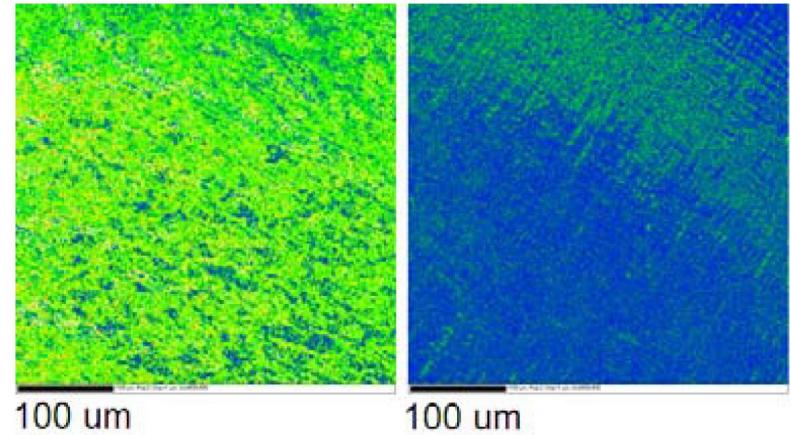
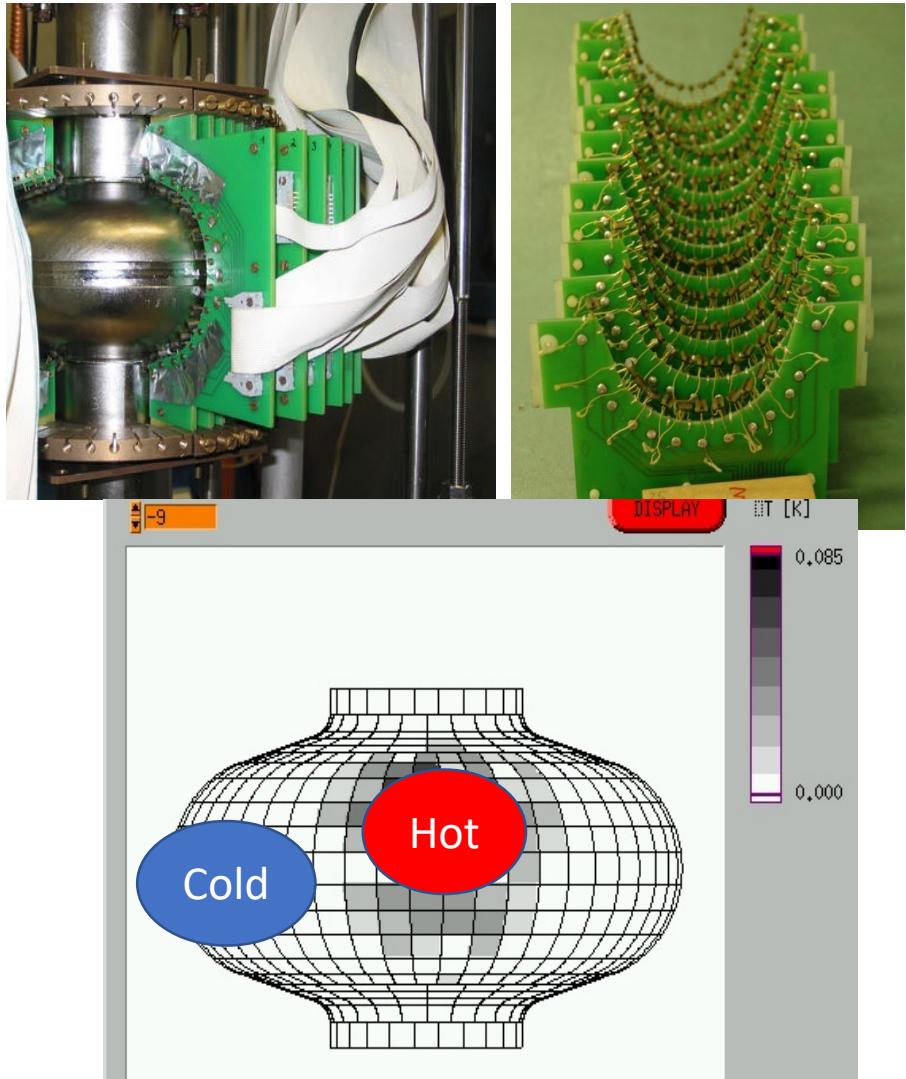
$B_z$  applied = 0.01



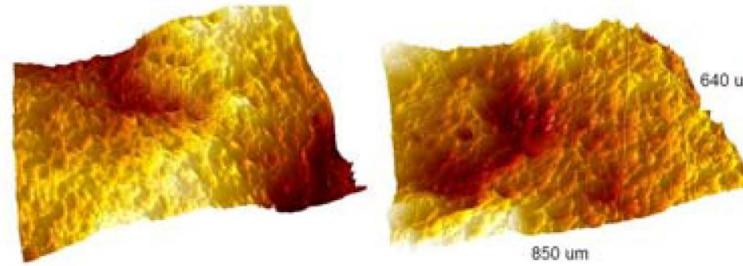
# Static Magnetic Field In and Around a Superconducting Sphere



# “Hot” and “Cold” Comparison



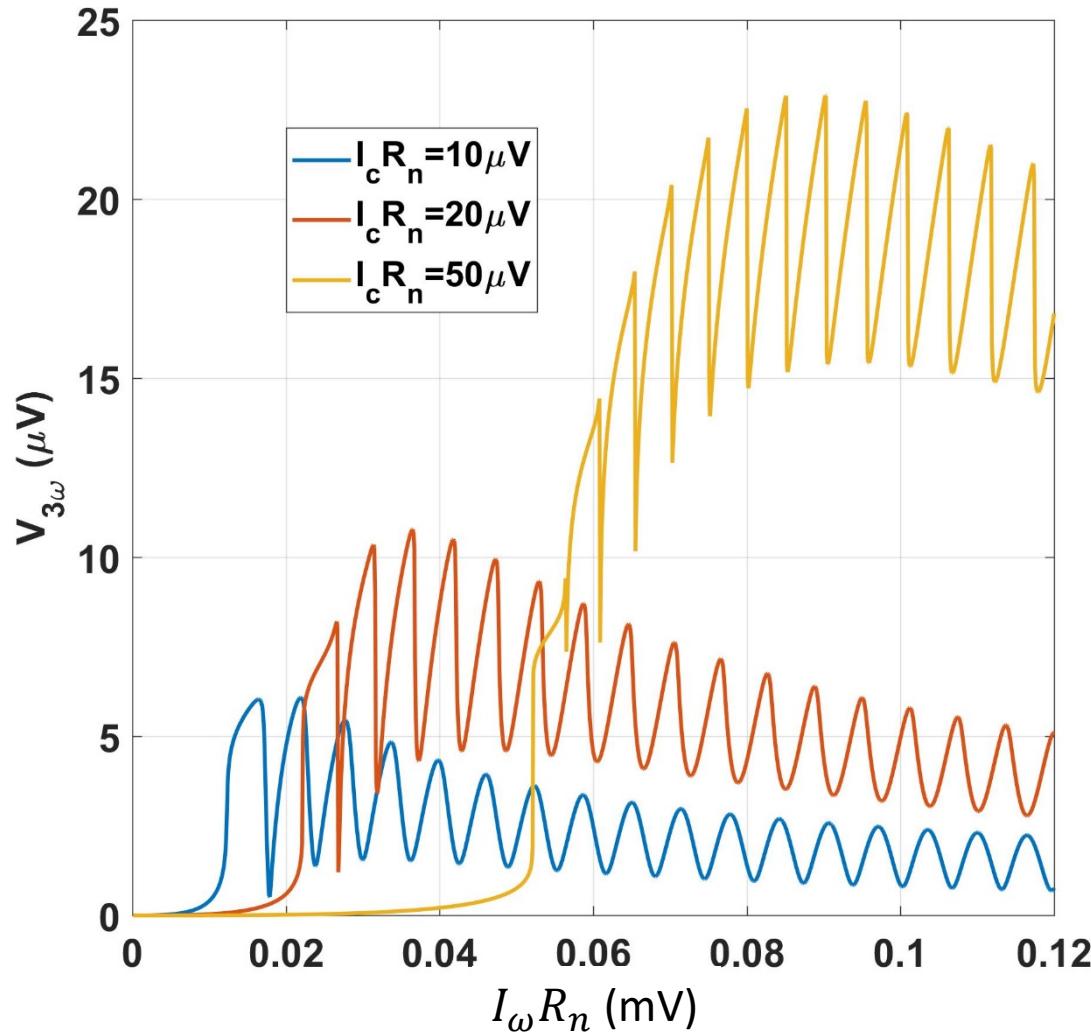
(EBSD) Local misorientation maps for “hot” (left) and “cold” (right) regions. Green color corresponds to  $2^\circ$  mis-orientation, blue -  $0^\circ$ .



Optical profilometry 3-D images ( $850 \mu\text{m} \times 640 \mu\text{m}$ ) of the hot (left) and cold (right) samples.

A. Romanenkt , G. Eremeev, D. Meidlenger, H. Padamsee “Studies of the high field anomalous losses in small and large grain niobium cavities”, Proceedings of SRF2007, Peking Univ., Beijing, China

RCSJ Simulation

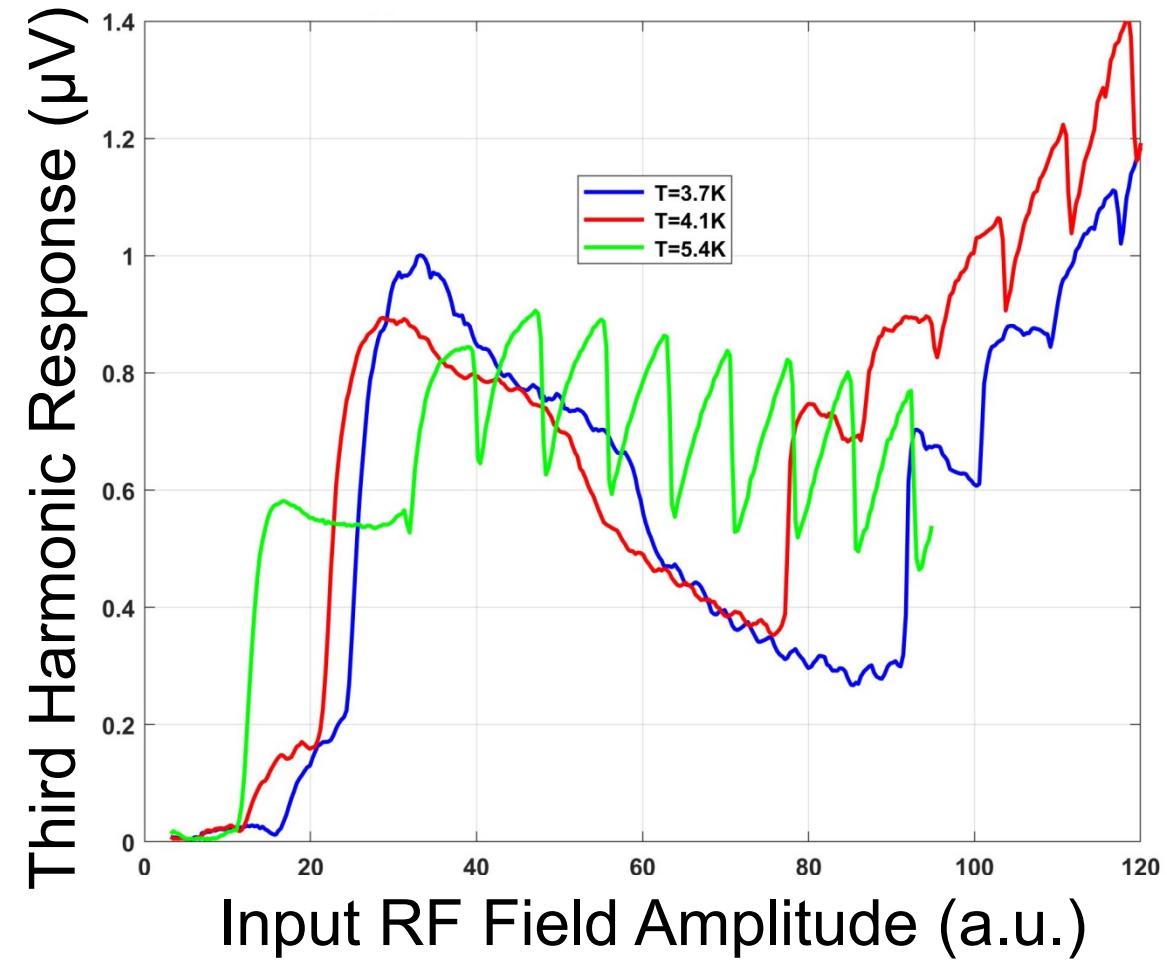


$$I_\omega R_n(\text{mV}) = \text{ScalingFactor} * \text{Input RF Field Amplitude (a.u.)}$$

**Onset(mV)** = ScalingFactor \* Onset (a.u.)  
**Period(mV)** = ScalingFactor \* Period (a.u.)  
**Dip #1(mV)** = ScalingFactor \* Dip #1 (a.u.)

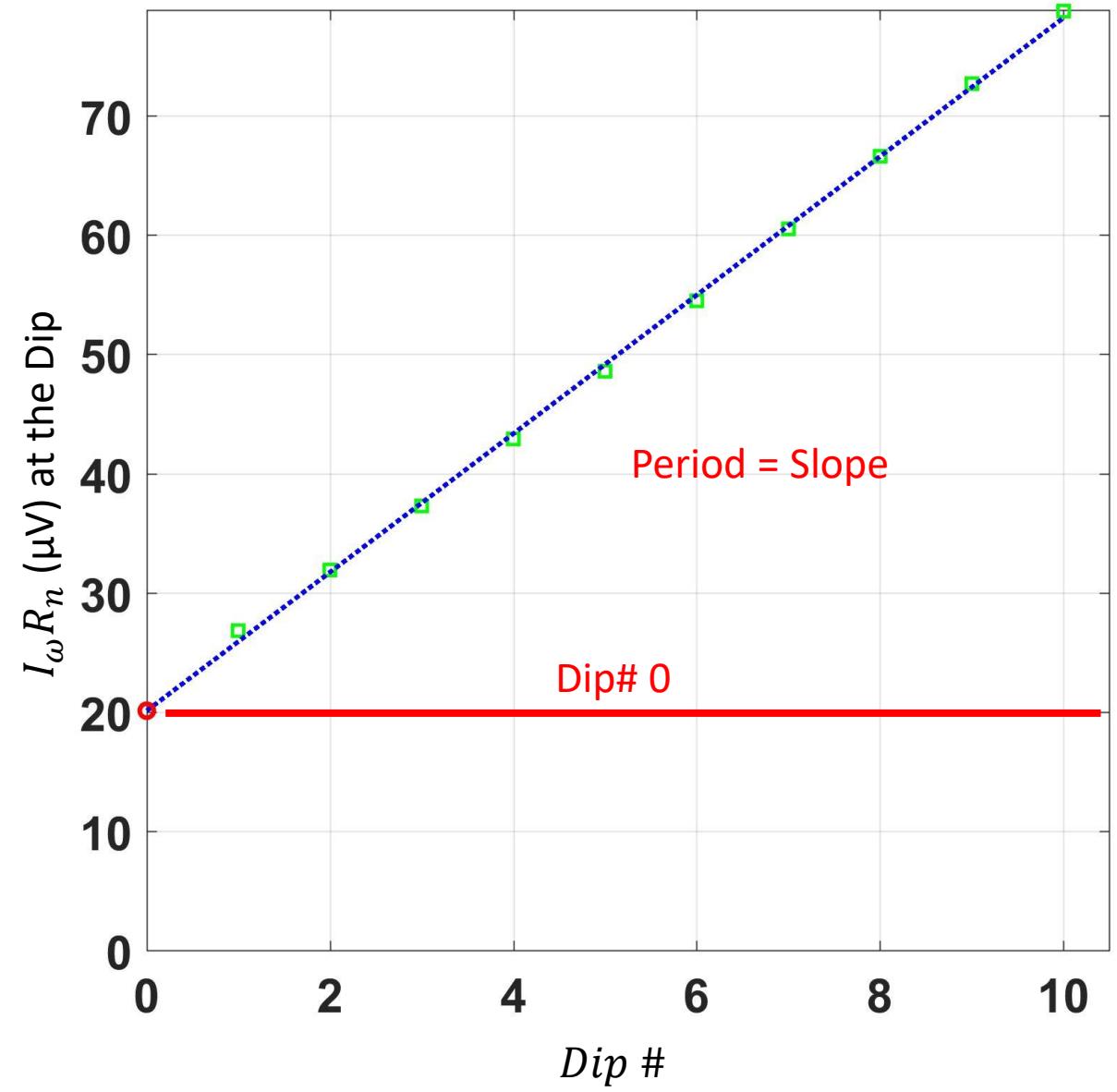
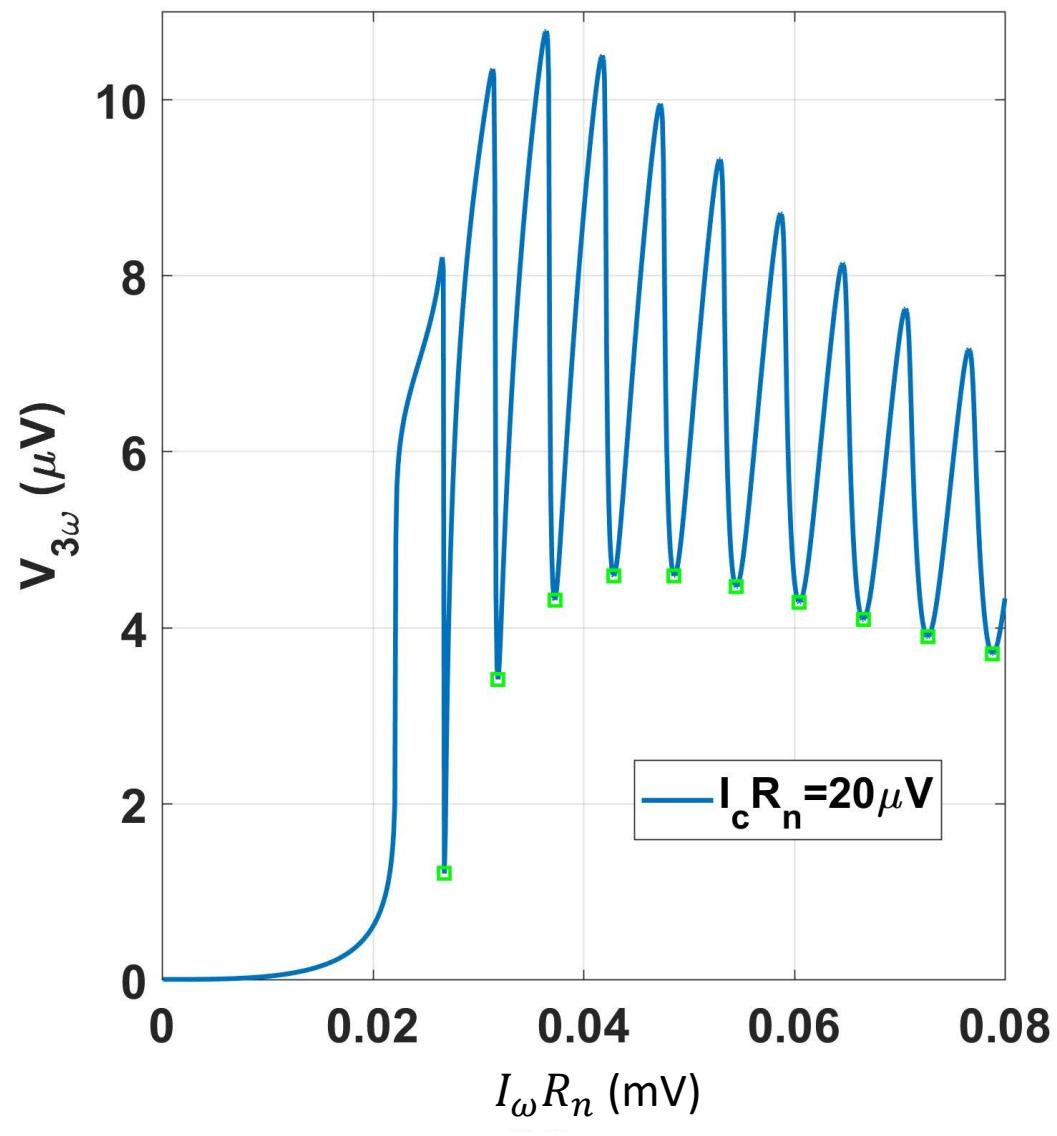
?

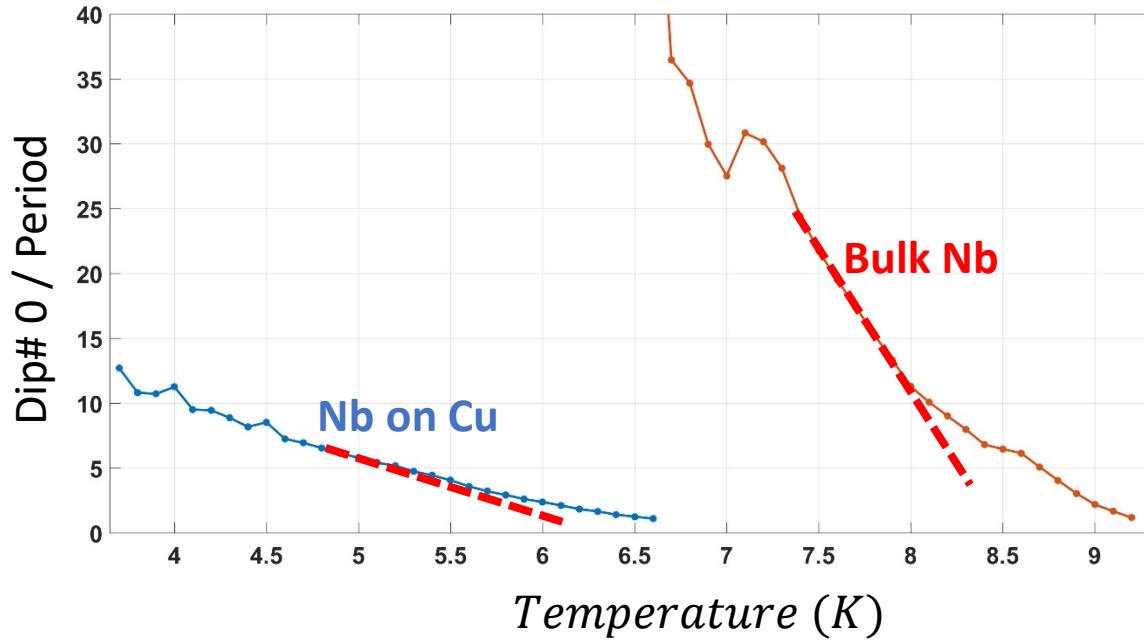
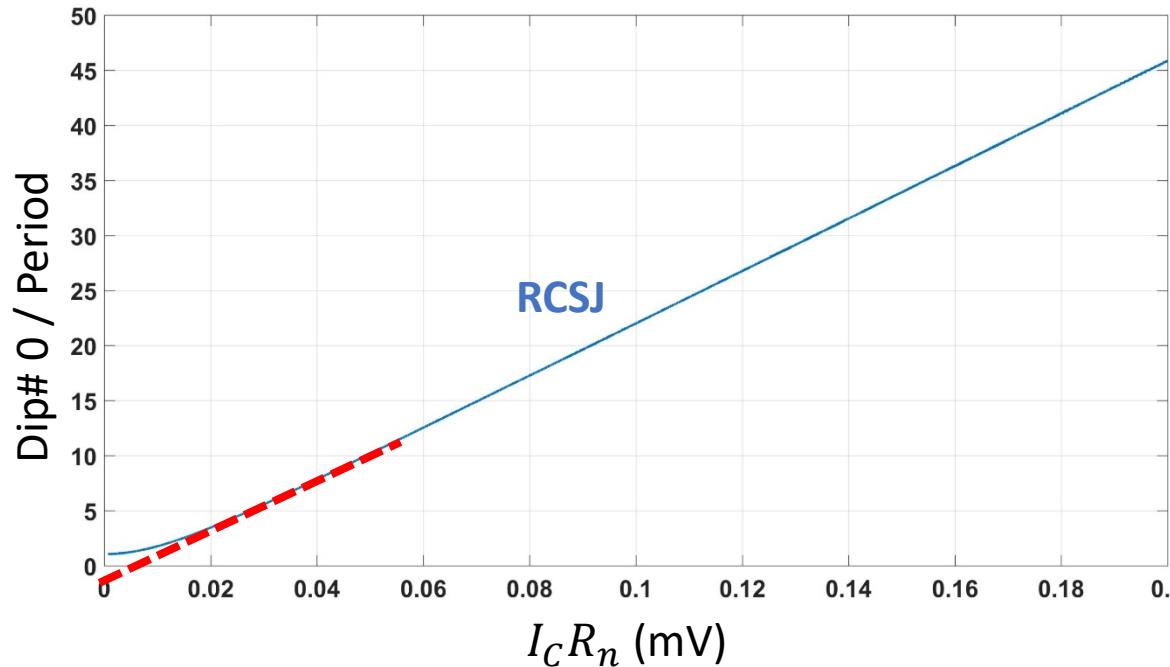
Nb on Copper Data



$$\frac{\text{Dip}\#0}{\text{Period}}$$

$(RCSJ \text{ Simulation at a given } I_c R_n)$   
 $(\text{Or Nb Data at a given Temperature})$



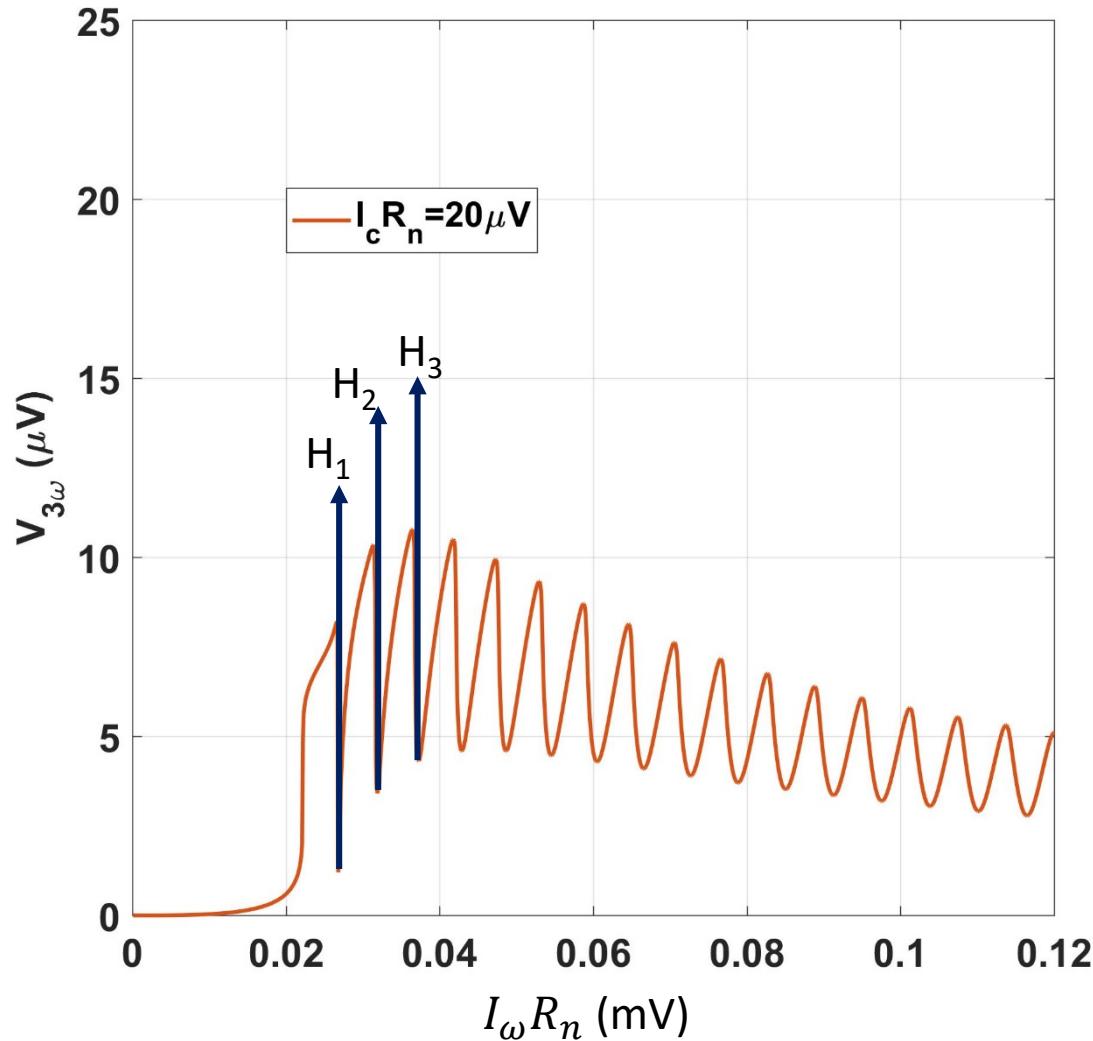


- 1) Taka Data at  $T$
- 2) Determine Dip# 0 / Period
- 3) Find Matching  $I_c R_n$



$I_c R_n$  (T)

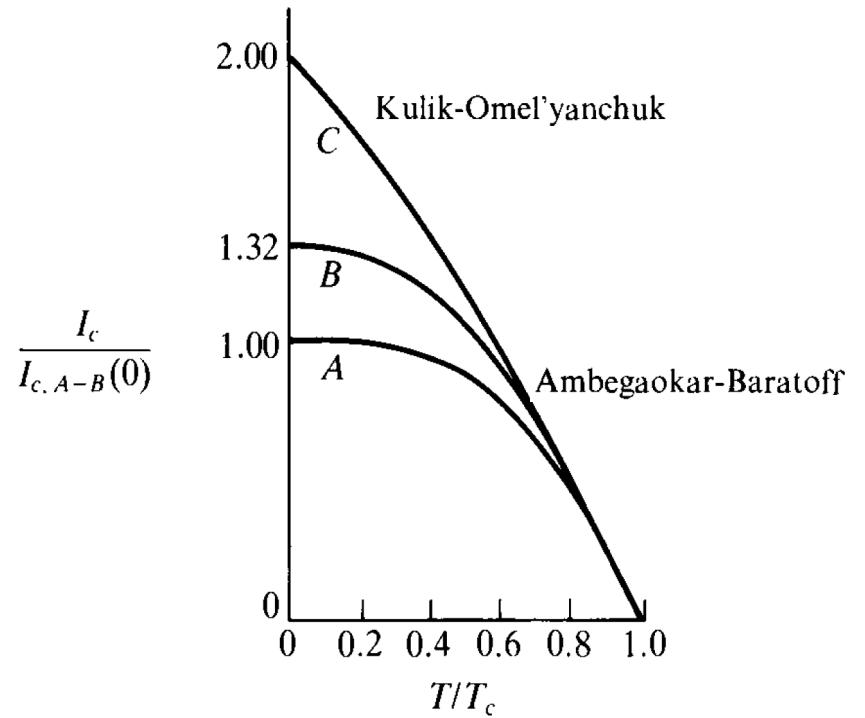
### RCSJ Simulation



# Getting $\Delta$ from Junction

SIS Junction Assumed:

$$I_C R_n = \frac{\pi \Delta}{2e} \tanh\left(\frac{\Delta}{2k_B T}\right) \quad \text{Ambegaokar-Baratoff}$$



Solve for  $\Delta$